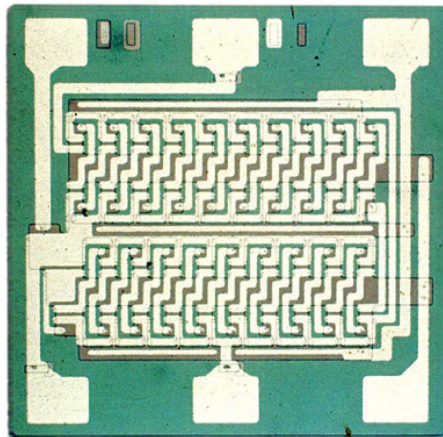
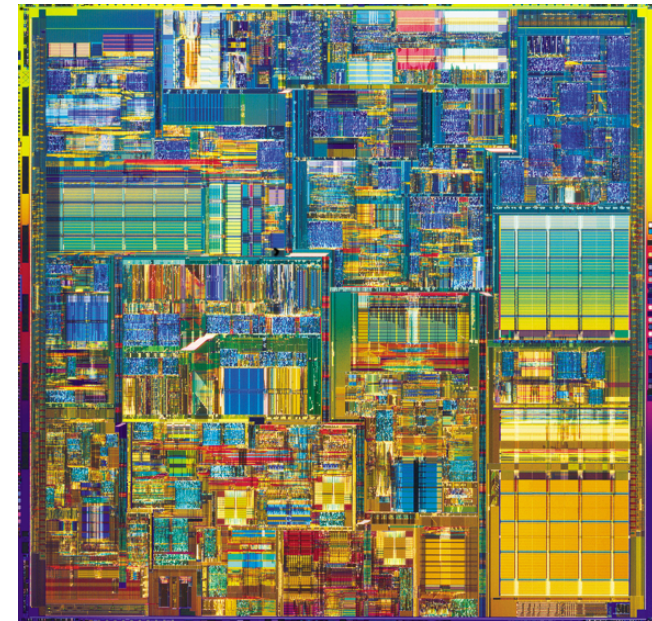


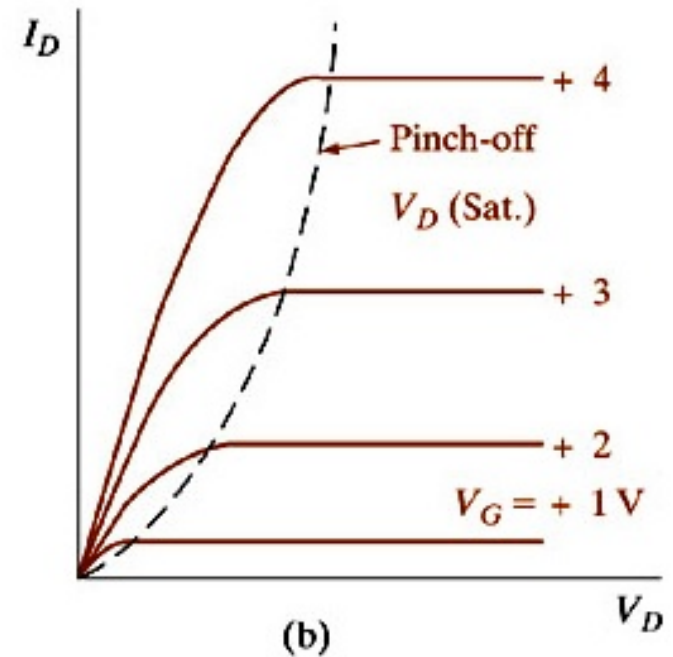
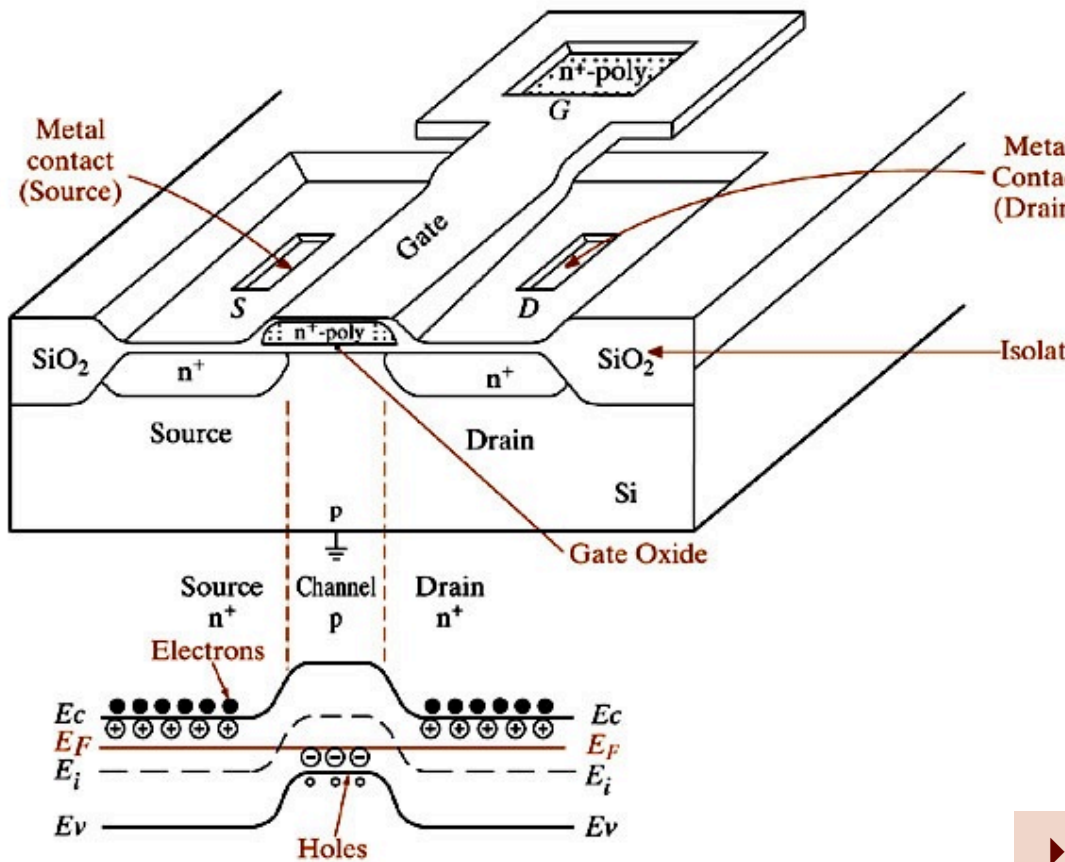
6.1– Transistor Operation

6.4.1 & 6.4.2 MOSFET Basics

Images for this lecture: 1st MOS IC (RCA, 1964), 1st commercial microprocessor (Intel 4004, 4 bit, 2,300 transistors, 92 kHz, \$60,1971), and a modern chip...

No other human artifact has been fabricated in larger numbers than MOSFETs!



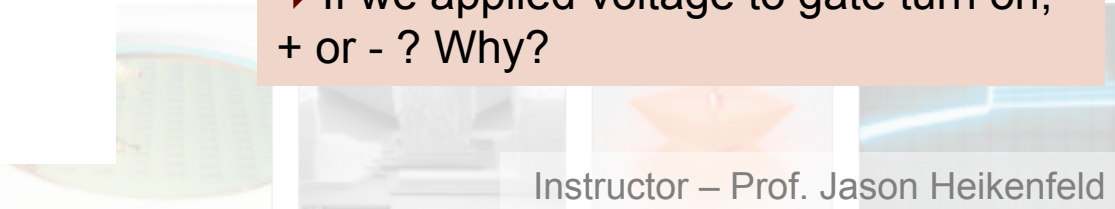


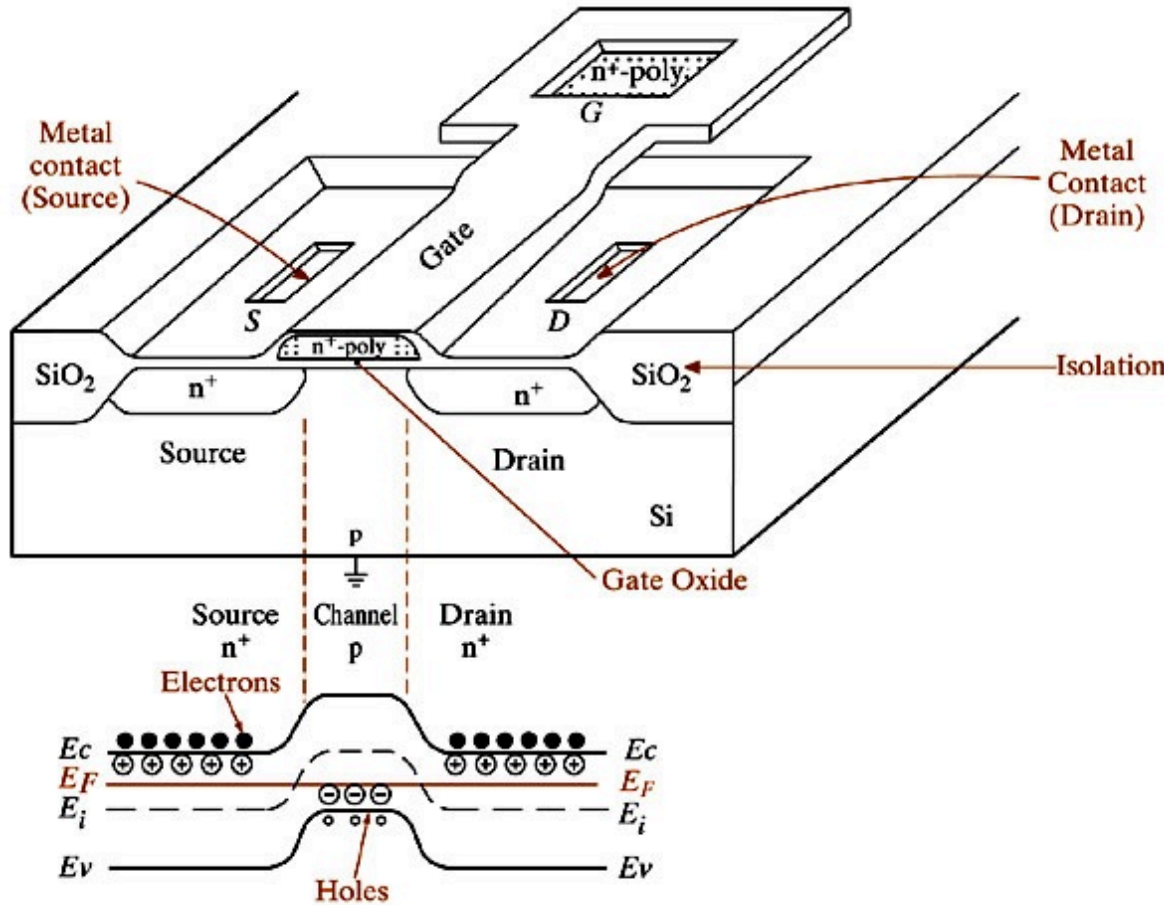
FABRICATION

- Substrate light doped p-Si
- n+ source/drain (diffused)
- thermal oxide (SiO₂)
- n+ poly-Si gate electrode (*thermally stable and best adhesion to oxides*)
- metal contacts (apertures)
- thick isolation oxide

► You already know enough to figure this out! So, tell me right now, why can't we get current flow from source to drain? ☆

► If we applied voltage to gate turn on, + or - ? Why?





OPERATION

- ▶ Fermi levels flat in equilibrium
- ▶ Built-in barrier forms and prevents electron conduction in channel... (back to back PN's!)
- ▶ Apply positive voltage, push bands down, provide a conductive channel for electrons to travel in...

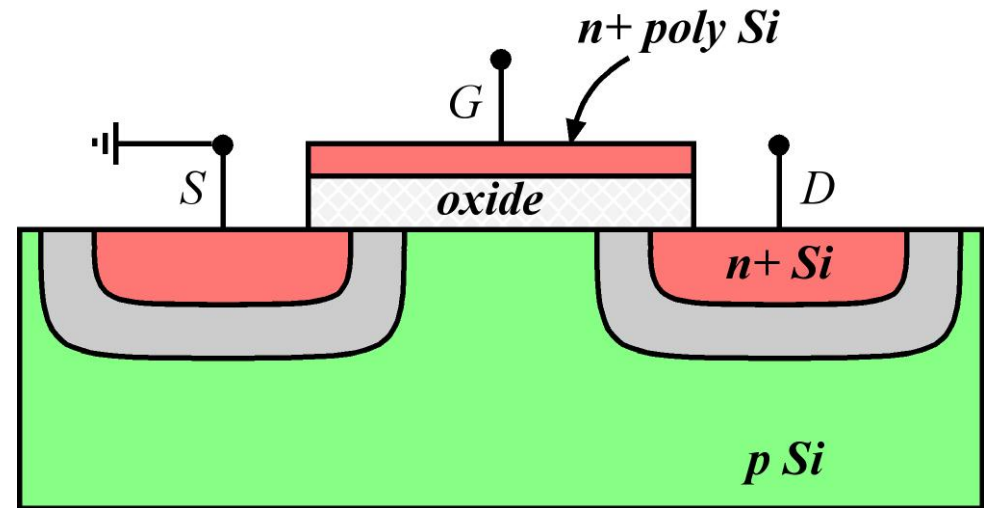
▶ MOSFET TYPES:

(1) *Enhancement mode n-channel device (at left)*
 ...normally OFF

(2) *Depletion mode*
 ...normally ON



- ▶ Unbiased device (*floating contacts*)
- ▶ Depletion regions formed between n+ and p, why n+? Two reasons...



- ▶ Now, even if we applied bias between drain and source these back-to-back diodes would prevent current flow

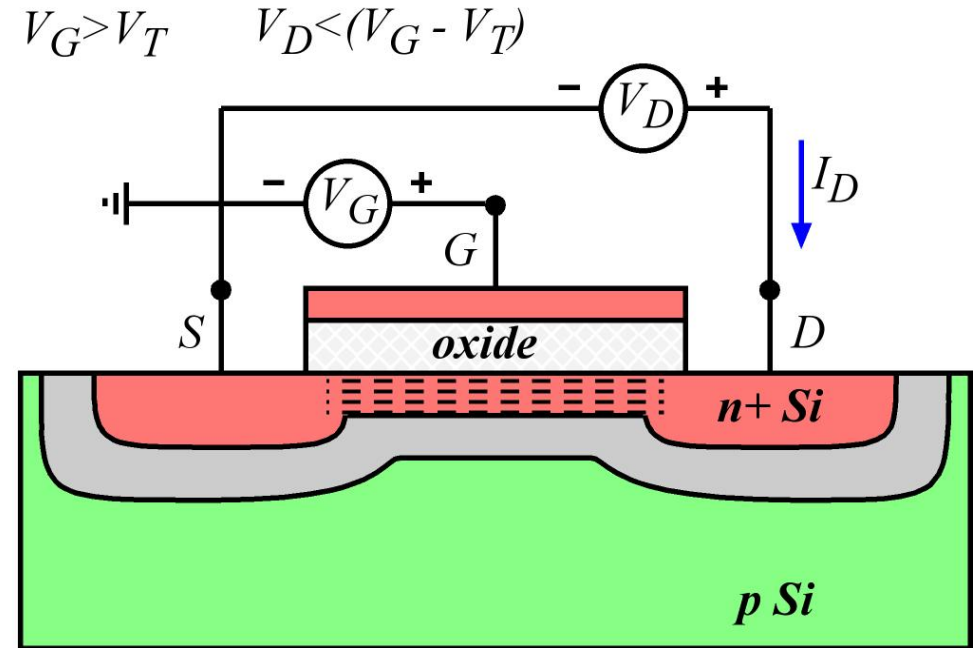
▶ So what is our ONLY option to get current flow from source to drain? Need to change the channel... We need to create lots of electrons in the channel (n-type!). ★

- ▶ What if we reversed all the doping types? ★

▶ If you can answer these questions then you are well on your way to understanding basic MOSFET principles!



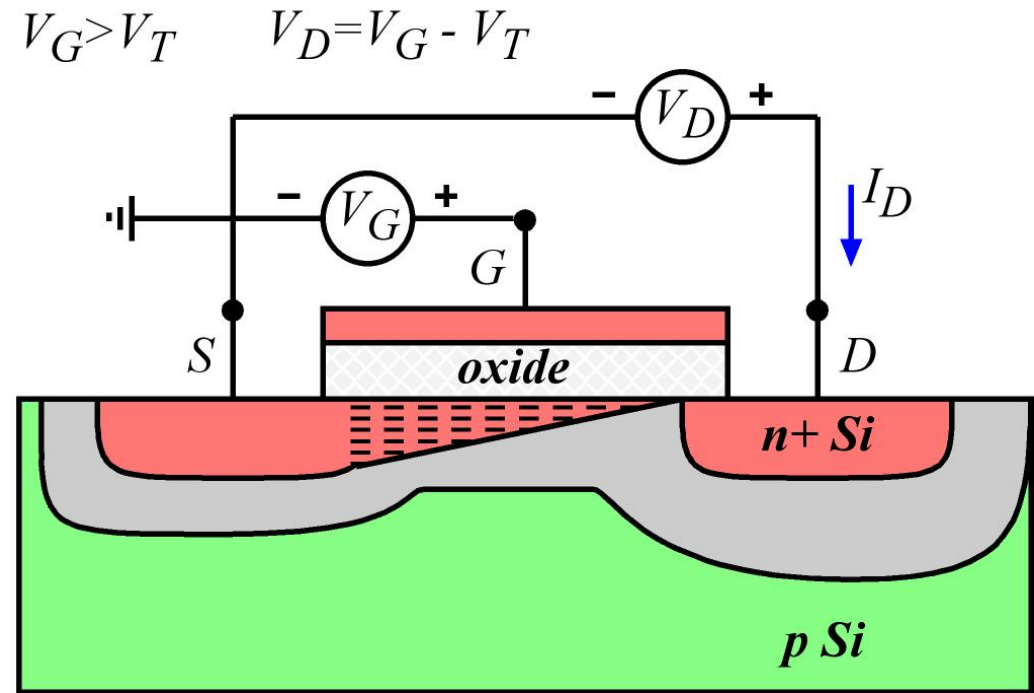
- ▶ Positive gate voltage (charge) greater than threshold voltage
- ▶ This requires negative voltage (charge) below gate oxide (capacitor charge up!)
- ▶ Small drain voltage to allow drift current (no substantial effect on PN junctions)



- ▶ Electron accumulation (*inversion*) forms a channel through which current can flow, source/drain current is allowed, oxide prevents any gate current...
- ▶ Electron accumulation mimics n-type material (hence why called NMOS), so a depletion region is formed outside channel
- ▶ This depletion region isolates the device from the substrate (which is good for multi-device integration, VLSI)



- ▶ Now we have increased our drain voltage significantly
- ▶ Like the JFET and MESFET at this point the current flow saturates, what happened?
- ▶ We can counteract this pinchoff by increasing gate bias

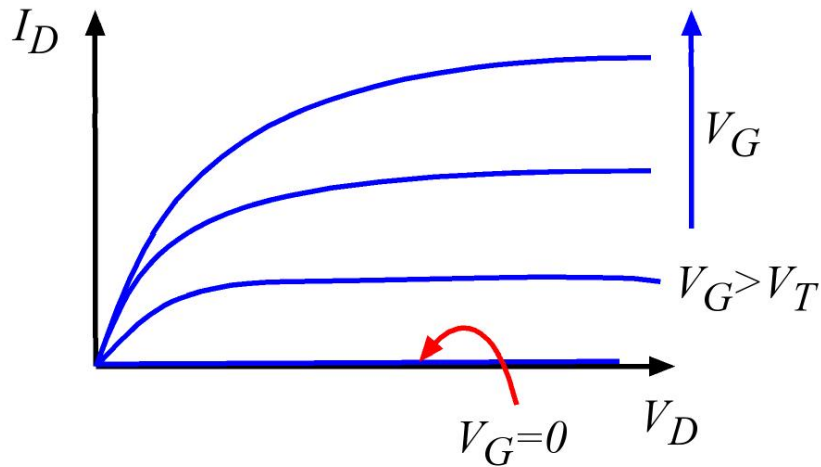


- ▶ Good animated example:

<http://www-g.eng.cam.ac.uk/mmg/teaching/linearcircuits/mosfet.html>



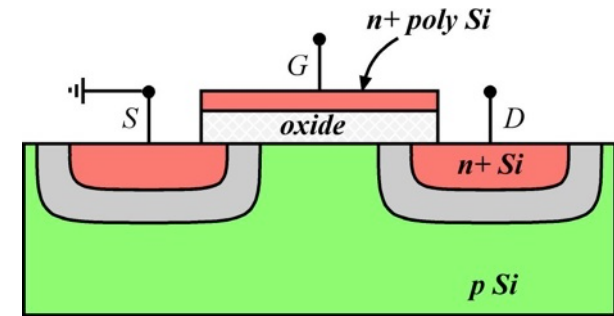
► Bringing it all together (review)



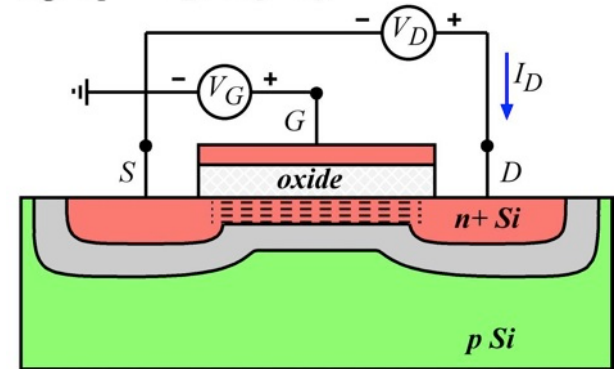
► We won't spend much time on $I(V_d)$ or even $I(V_g)$! all we care about normally is V_t . why?
Think about the applications...

► To do this, we need to answer how inversion creates electrons in a p-type material (and we have no current injection, just a capacitor). What has to shift?

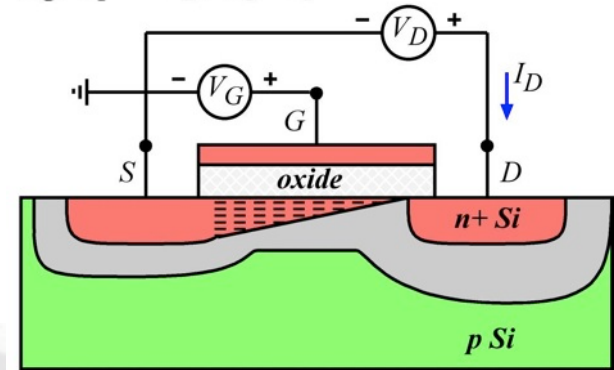
► Lets derive V_t , hang in there...



$V_G > V_T \quad V_D < (V_G - V_T)$



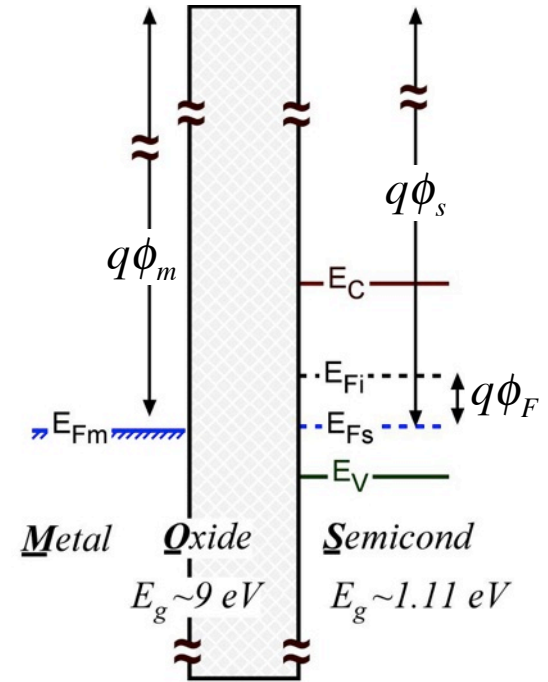
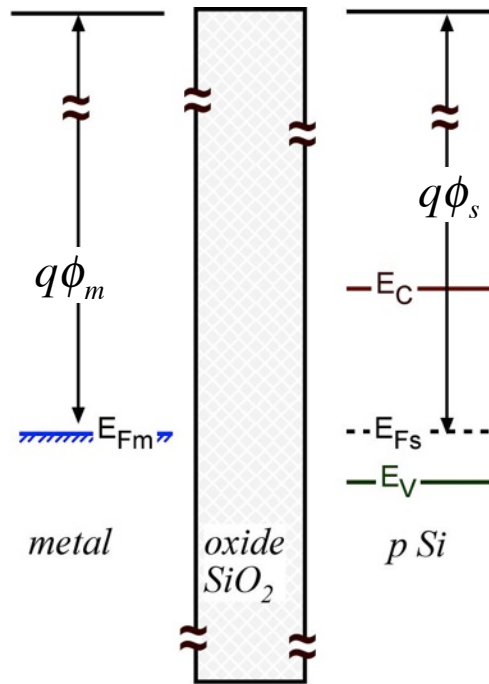
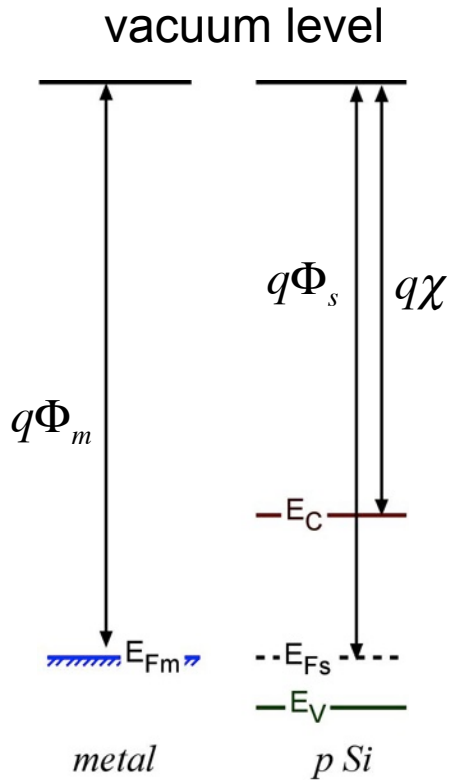
$V_G > V_T \quad V_D = V_G - V_T$



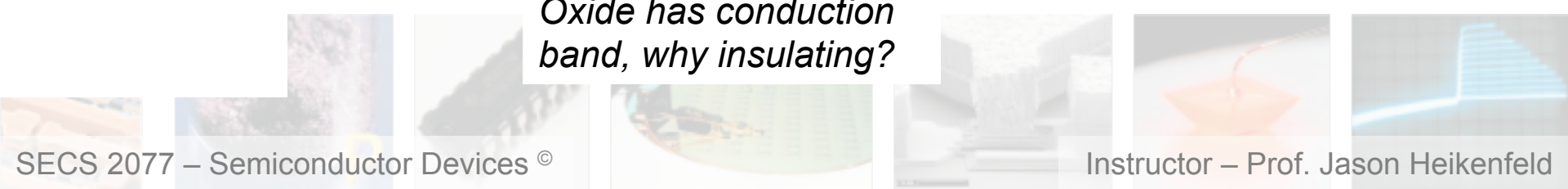
► Assume $q\Phi_m$ $q\Phi_s$ are relatively equal.

► For convenience use modified work functions (lower case) measured with respect to E_c of oxide.

► Also note $q\phi_F$



Oxide has conduction band, why insulating?

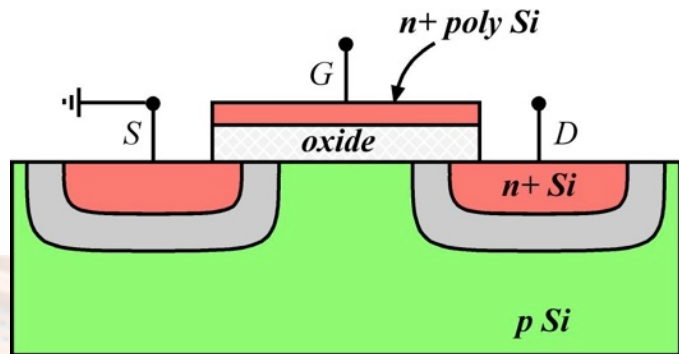
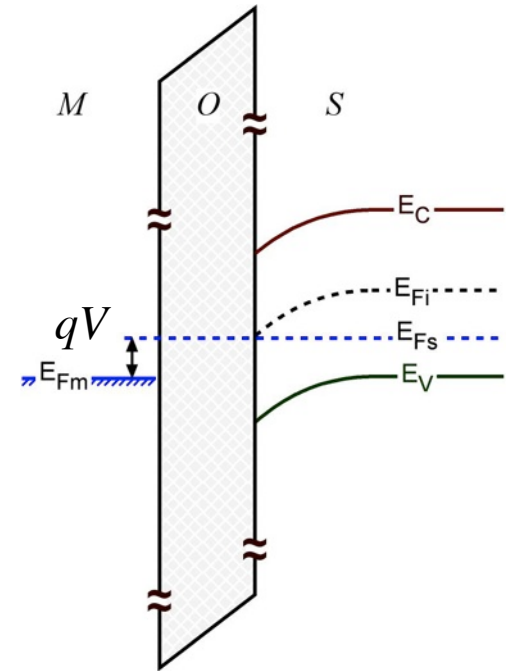
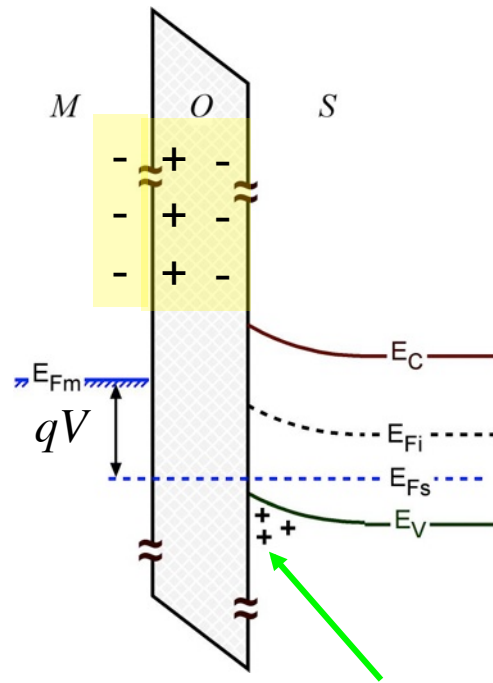
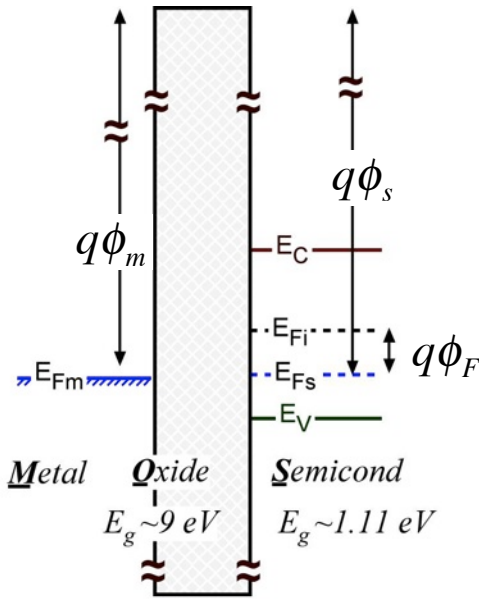


▶ For metal/oxide/p-type Si... voltage applied to metal... V drop across oxide (slope)

▶ Equilibrium (V=0)

▶ Accumulation (V<0)

▶ Depletion (V>0)



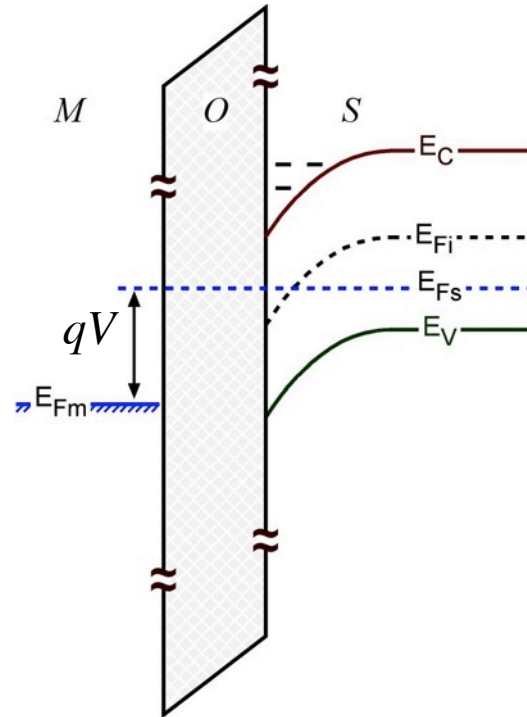
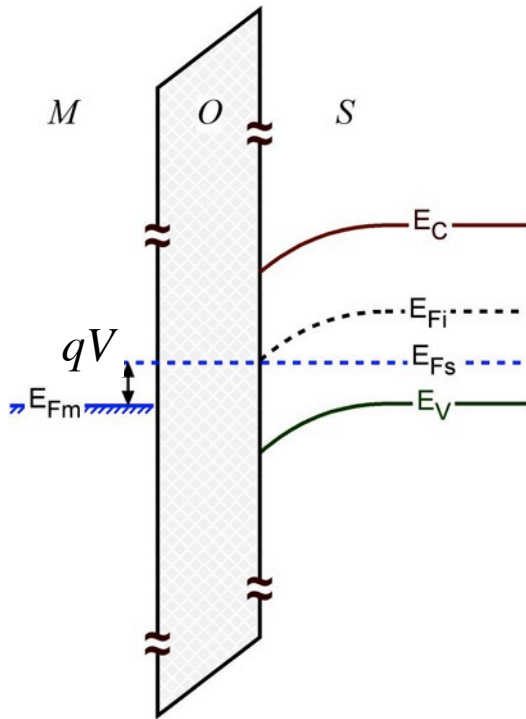
▶ Here is a channel of holes! why won't this help us?

▶ Wait, I said (+) gate bias would get us e' s? Why don't we have any? How many e' s can drift? Lots? Few? **Lets derive V_{th} !**

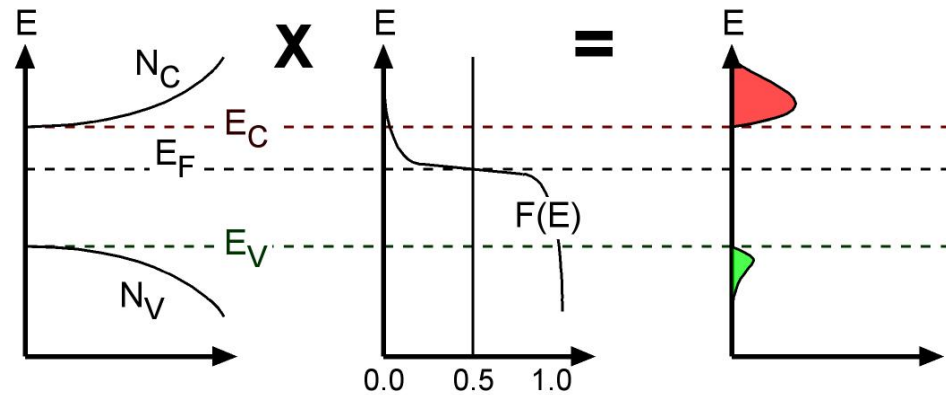
▶ *Back to back PN junctions!* ☆

▶ Depletion ($V > 0$)

▶ We need Inversion ($V \gg 0$)!



▶ Under inversion the Fermi-level near oxide is closer to the conduction band than the valence band! Makes sense!



► However, to form a true n-type conducting channel (n+) we need to have **Strong Inversion**

the surface should be just as n-type as it was originally p-type... (will explain why in a moment)

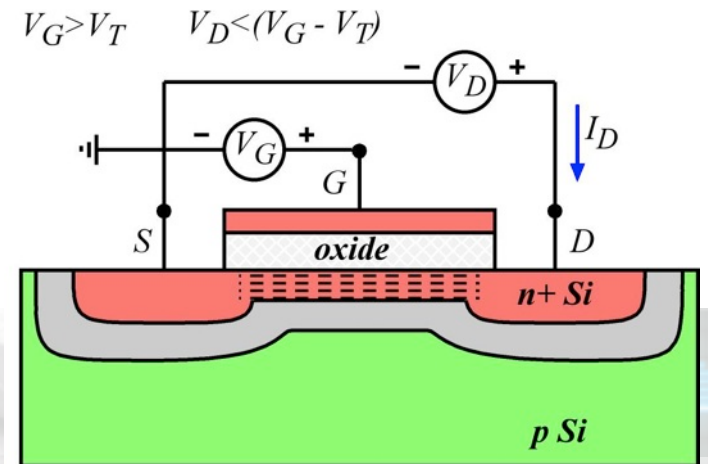
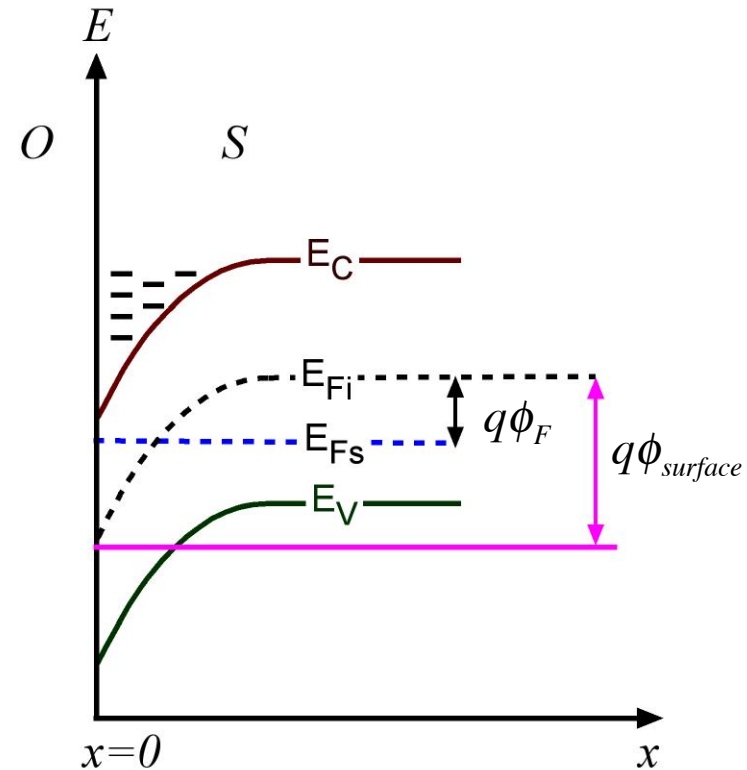
... E_{Fi} should be just as far below E_{Fs} at the surface as it is above E_{Fs} in the bulk

Another way to put this is that to get strong inversion we need the surface potential ($\phi_{surface}$) to be twice the Fermi offset (ϕ_F).

$$\phi_{surface} (inv.) > 2\phi_F = 2 \frac{kT}{q} \ln \frac{N_a}{n_i}$$

Again, we will see why we need $2\phi_F$ in a moment...

Hmm.... Surface potential (sounds like it will be part of our threshold voltage). This will also make sense later! Stay tuned!



▶ The channel conductivity is based on the electron concentration, lets calculate...

▶ In the bulk:

$$n_0 = n_i e^{(E_f - E_i) / kT}$$

$$= n_i e^{-q\phi_F / kT}$$

▶ As a function of x: $q\phi$

$$n = n_i e^{-q(\phi_f - \phi) / kT}$$

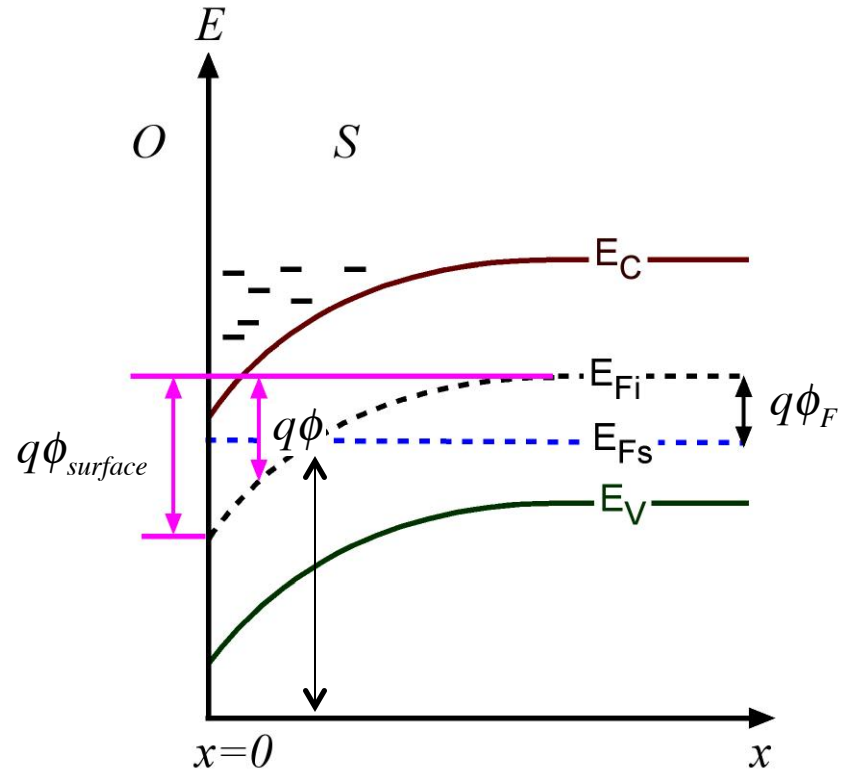
$$= n_i e^{-q\phi_f / kT} e^{q\phi / kT}$$

$$= n_0 e^{q\phi / kT}$$

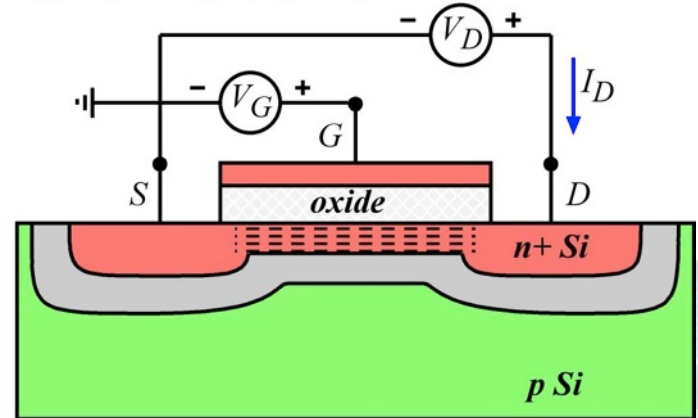
▶ Same approach for holes...

$$p = p_0 e^{-q\phi / kT}$$

▶ Near surface, what does this tell us for n, p? Device at right I(V_G)? ☆



$$V_G > V_T \quad V_D < (V_G - V_T)$$



- Use Poisson's equation (ϕ for V), what does this mean?

$$\frac{\partial^2 \phi}{\partial x^2} = -\frac{\rho(x)}{\epsilon_s}$$

the typical charge density:

$$\rho(x) = q(N_d^+ - N_a^- + p - n)$$

and the relation:

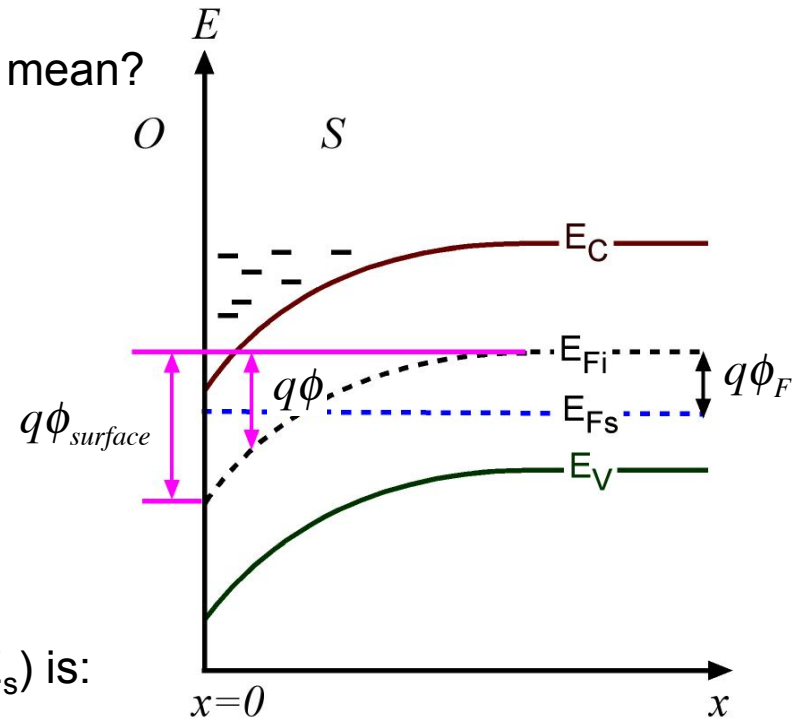
$$E = -\frac{\partial \phi}{\partial x}$$

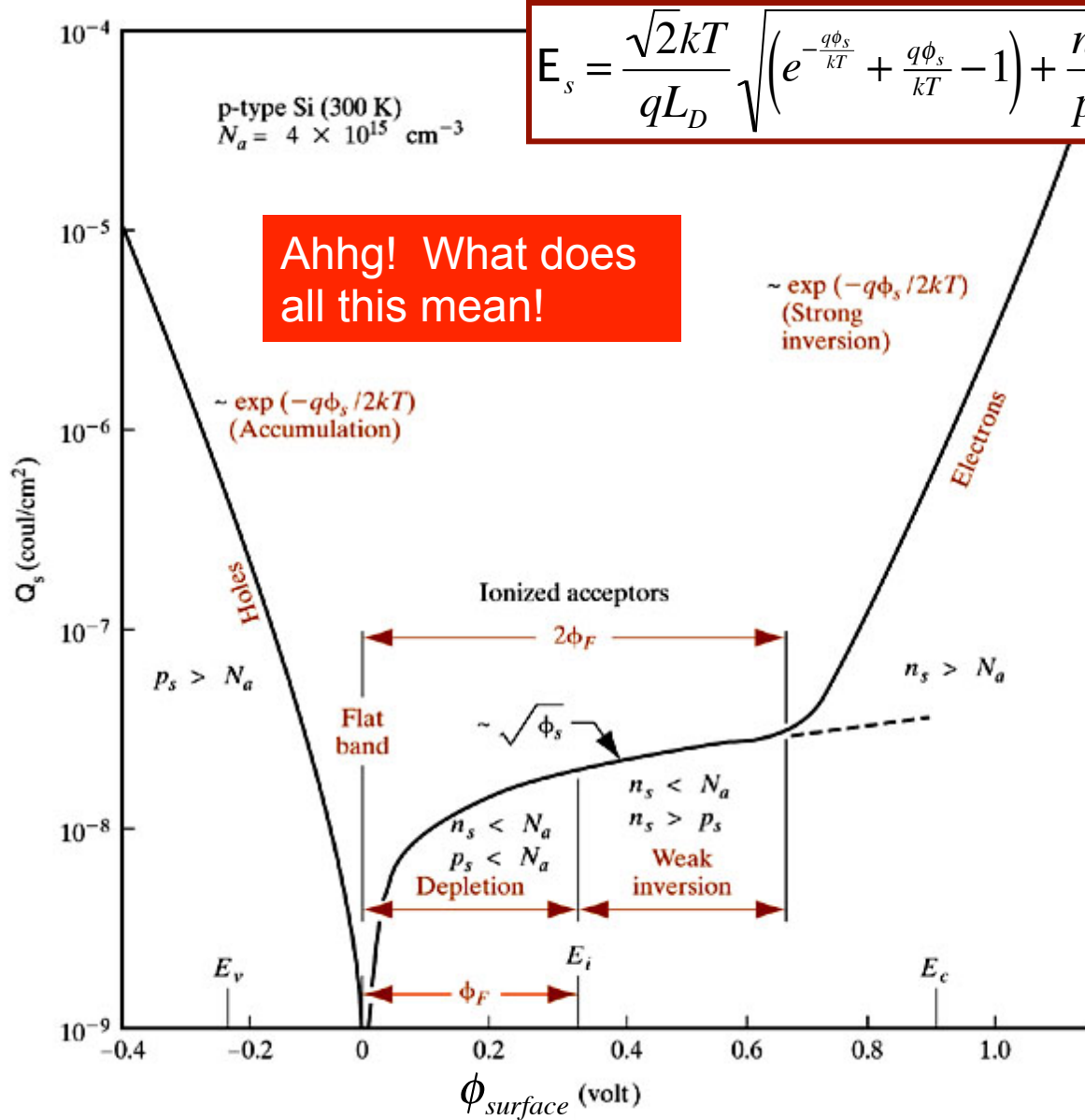
it can be shown that at the surface and perpendicular to the surface ($x=0$) that the E-field (E_s) is:

$$E_s = \frac{\sqrt{2kT}}{qL_D} \sqrt{\left(e^{-\frac{q\phi_s}{kT}} + \frac{q\phi_s}{kT} - 1 \right) + \frac{n_0}{p_0} \left(e^{\frac{q\phi_s}{kT}} - \frac{q\phi_s}{kT} - 1 \right)} \quad L_D = \sqrt{\frac{\epsilon_s kT}{q^2 p_0}}$$

- L_D is the Debye length. It comes up a lot in electrostatics.

We cannot bring all the electrons to $x=0$, diffusion forces want to push them away.... (look inside the equation, for really heavy doping L_D is small, why?).

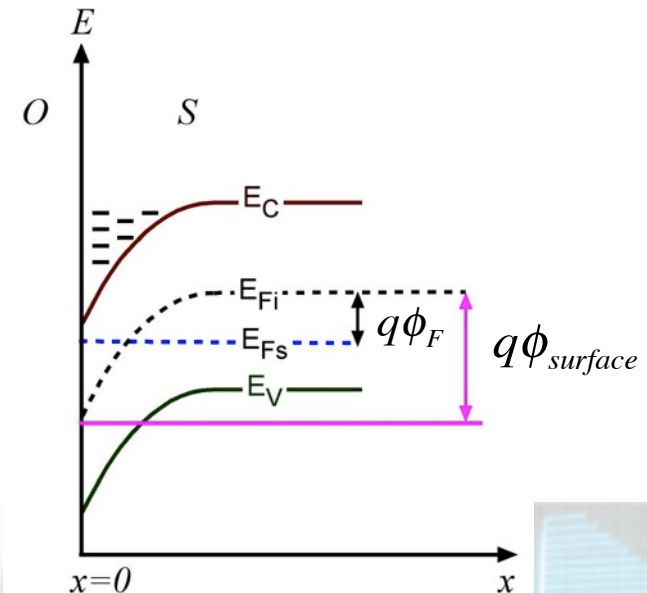




► We can apply Gauss' Law at the surface

$$Q_{surf} = -\epsilon_s E_{surf} \text{ (coul/cm}^2\text{)}$$

► Note, this plot is only at the surface (x=0)




▶ KEY!!!!

To understand this plot...

- and capacitance vs. voltage,
- and charge distribution vs. voltage,
- and threshold voltage,

we must understand that there are a series of events that take place in biasing the MOSFET:

Accumulation <-> Flatband <-> Depletion <-> Inversion

You cannot move to one state, without having passed through the other.  This will have a large implication on capacitance (switching speed) and theshold voltage!



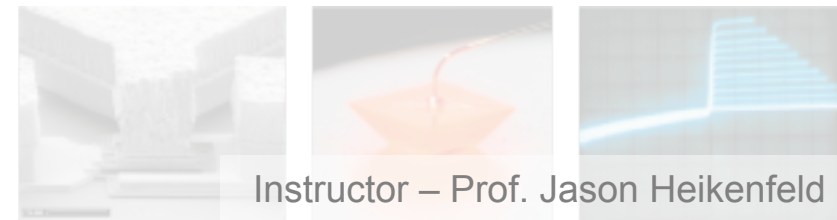
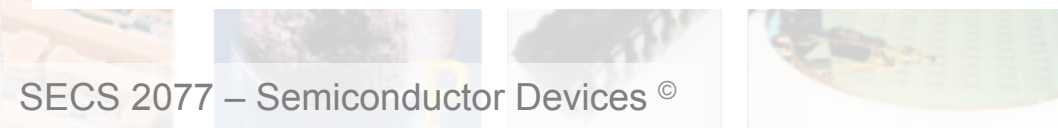
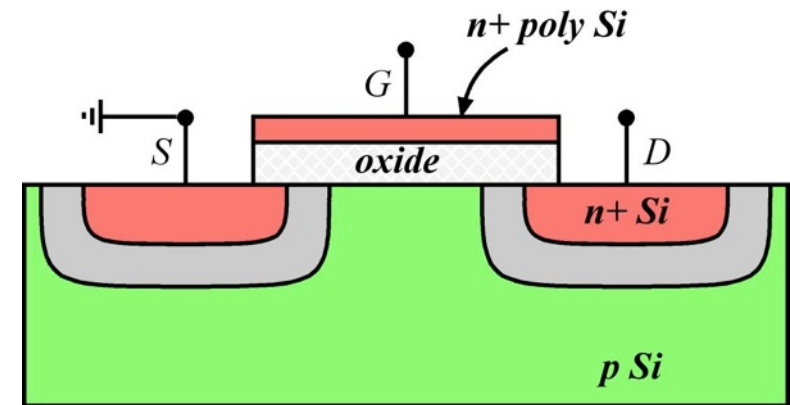
► Why can't I get current flow from source to drain without gate voltage? *No hint needed, answer should be obvious now!*

► If I apply negative voltage to the gate what will happen? Why no source-drain current? *Hint: negative voltage is negative charge on the gate electrode, which on the other side of the capacitor is therefore positive charge (holes).*

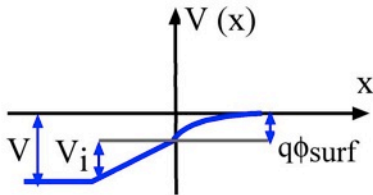
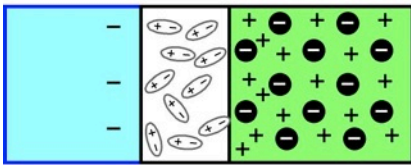
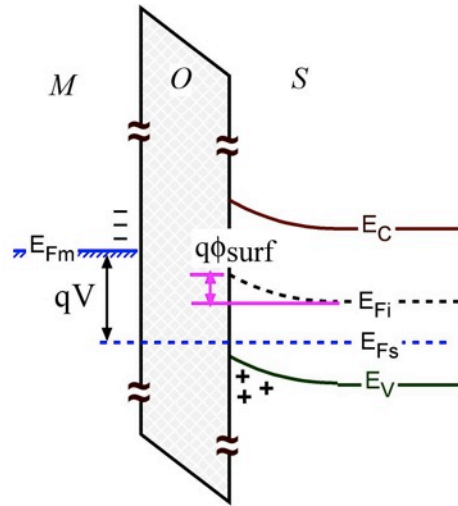
► If I apply positive voltage to the gate, what happens BEFORE the MOSFET is turned on? *Hint: before you get electrons (n-type channel), you first get something that still does not allow source-to-drain current, what is it?*

► If the MOSFET is on and I keep increasing the source drain voltage, what will happen and why? What type of current flow is this? *Hint, answer with the same terms we used for previous transistors!*

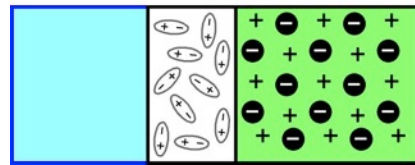
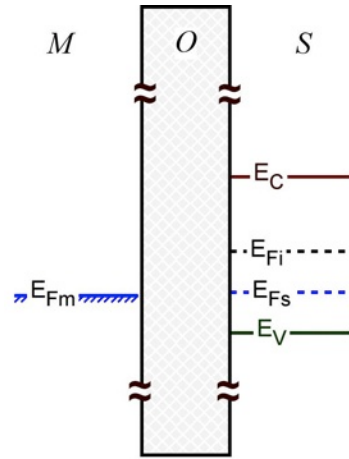
► The MOSFET at right is NMOS, why called NMOS? *No hint needed!*



► Accumulation

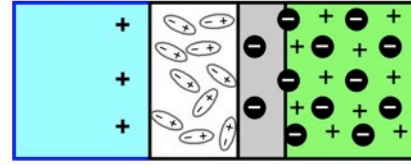
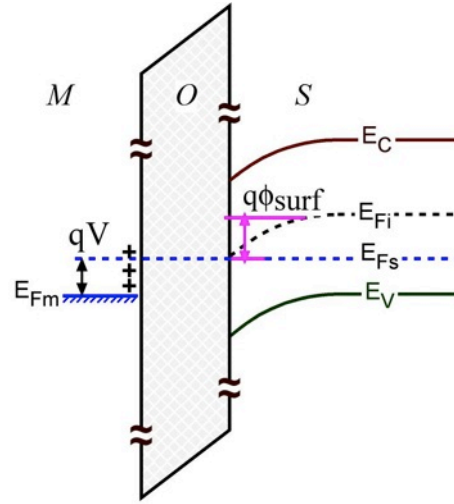


► Flat Band

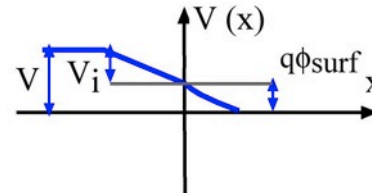


Note how draw dipoles inside dielectric...

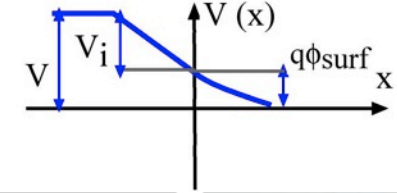
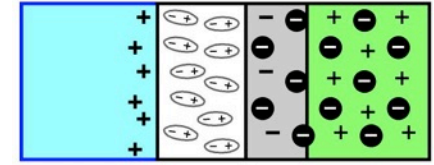
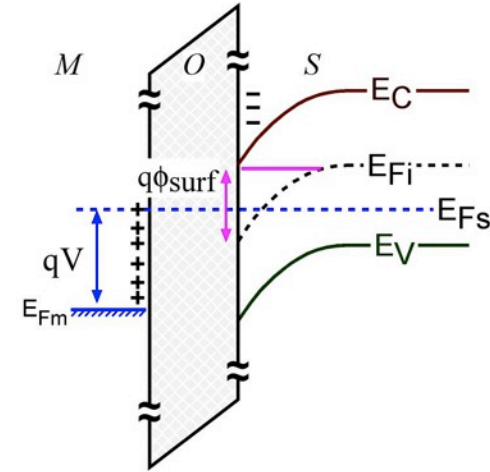
► Depletion & Weak Inversion



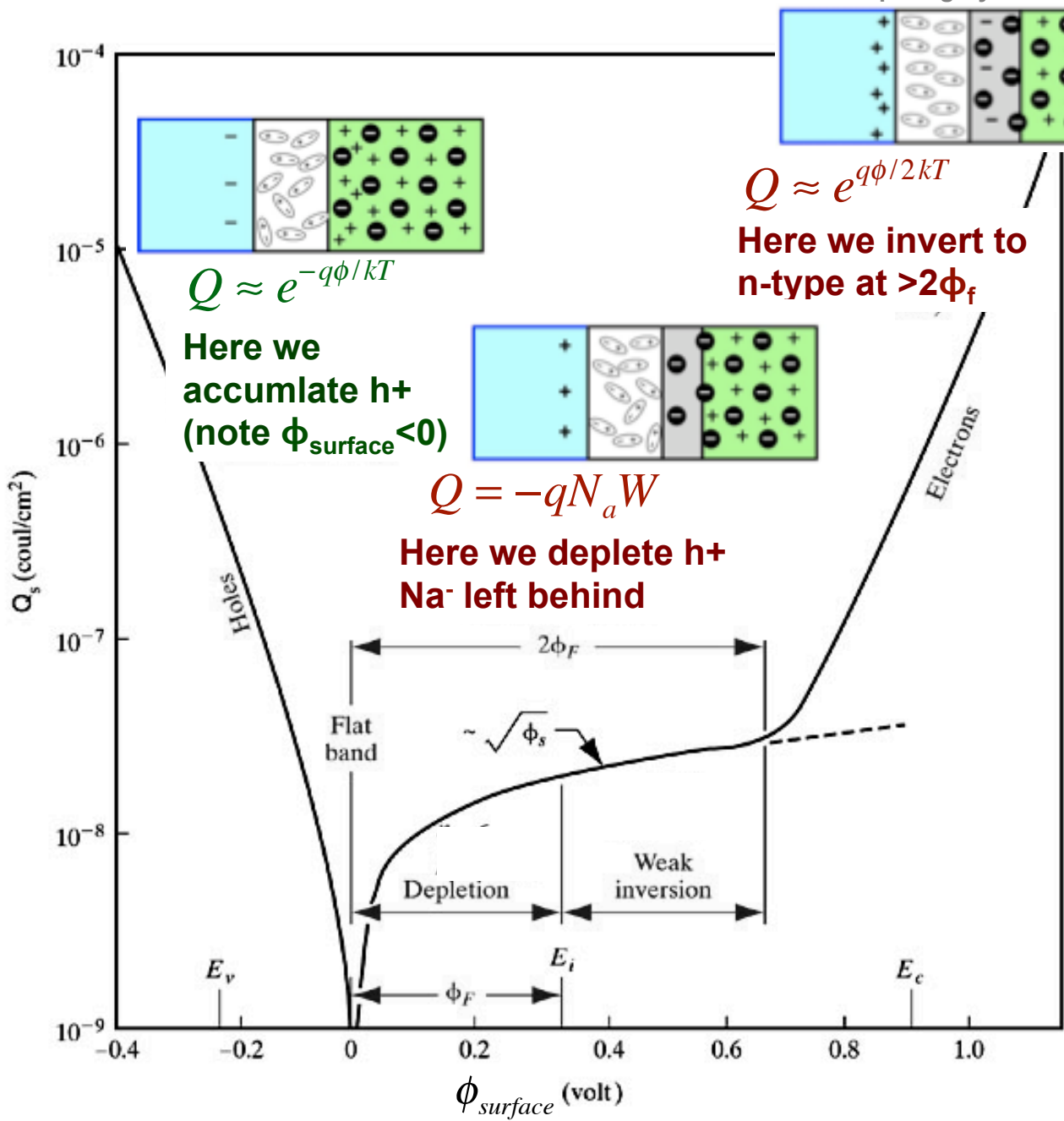
charge, but no channel!



► Inversion

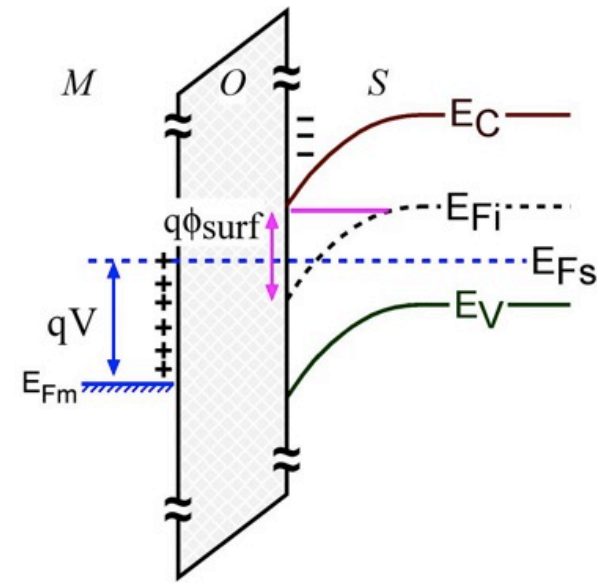
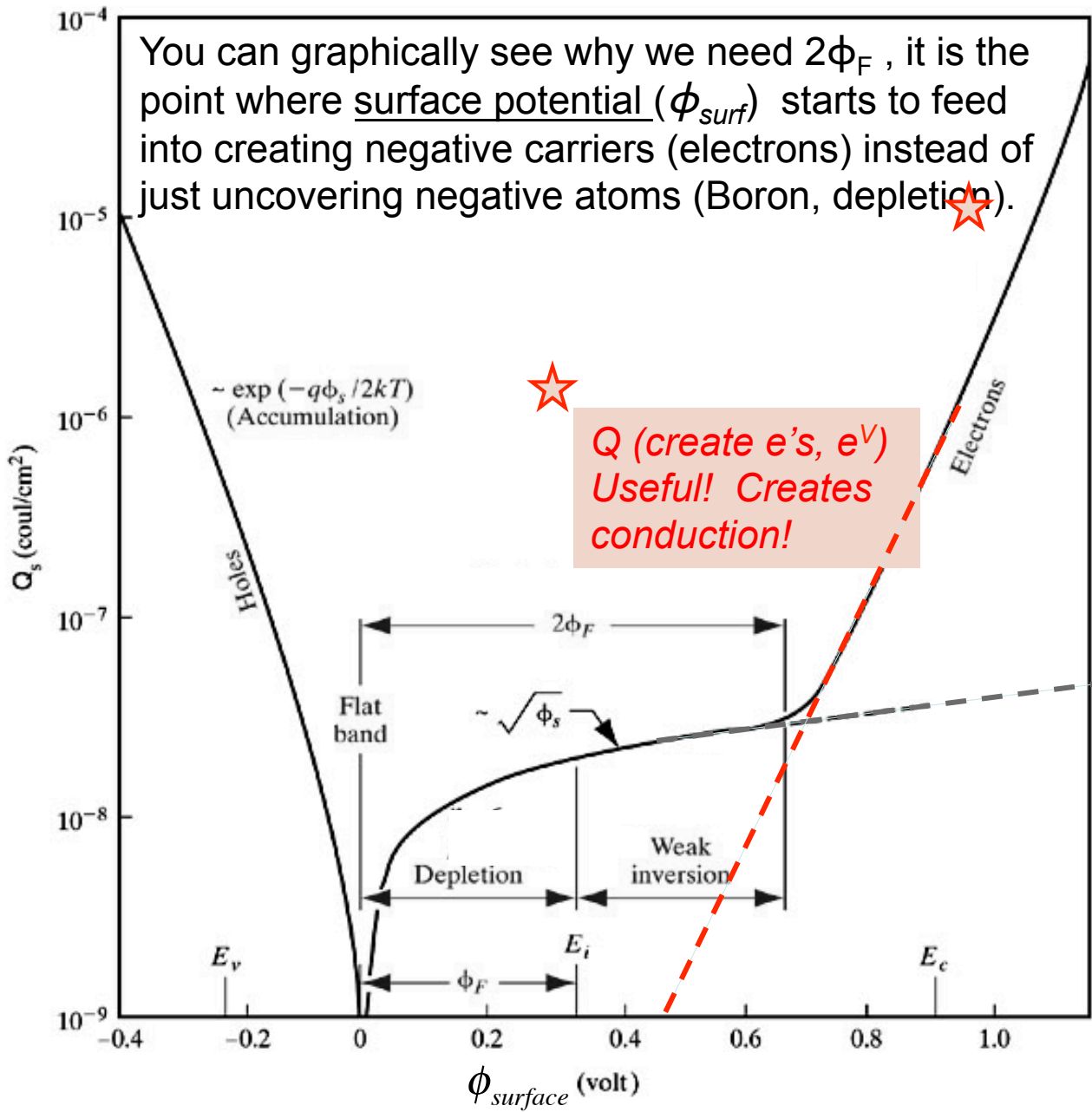


Straight band bend = constant V drop (constant E), curved band = non-constant V drop...
Curved for semicon. because contributing charge decreases (and screens) as get toward edge.



But, why do we need to still pay for $2\phi_F$ of voltage before we can get the n-type channel to form?





★ Q (deplete + h's and leave behind - Borons, $V^{1/2}$)
this created Q is not useful for us...



▶ Similar to what we did with the PN junction, lets plot Q, E, V for the MOS capacitor... WHY IS Q IMPORTANT?

- speed! power!

▶ Charge on metal side:

- high-density thin layer (Q_m , positive)

▶ Charge in dielectric is zero (dipoles)

▶ Charge in p-type semiconductor is:

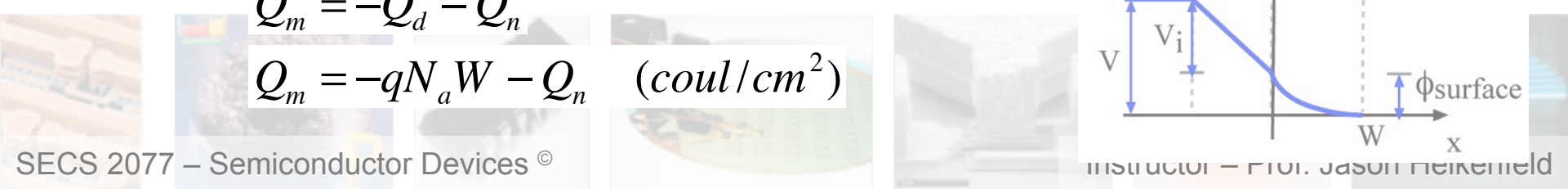
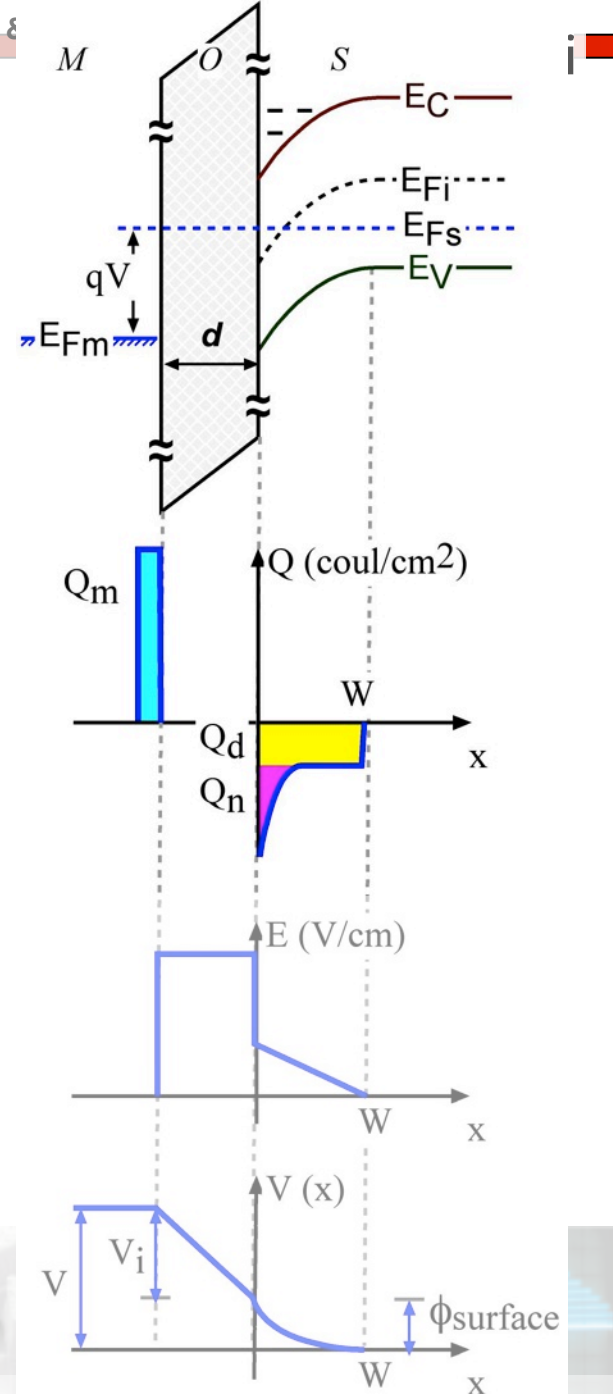
- depletion (Q_d , uncompensated ionized acceptors, N_a^- , negative)

- inversion (Q_n , electrons, negative)

- Why Q zero for $x > W$? ☆

$$Q_m = -Q_d - Q_n$$

$$Q_m = -qN_a W - Q_n \quad (\text{coul/cm}^2)$$



► Note, channel is exaggerated in figure at right, typically it is only ~10 nm.

► Our applied voltage is split up as voltage across the oxide insulator and the bands (both are sloped, right?!):

$$V = V_i + \phi_{surface} \quad C = \frac{\epsilon A}{d} \quad V_i = Q_i / C_i$$

V_i is

wasted... V_i will be part of the price we have to pay for V_T

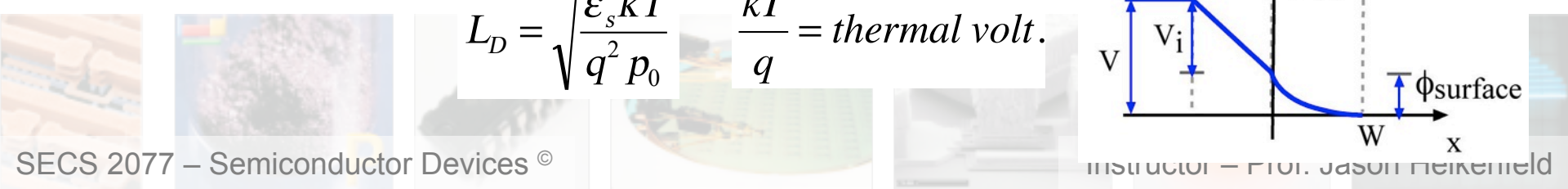
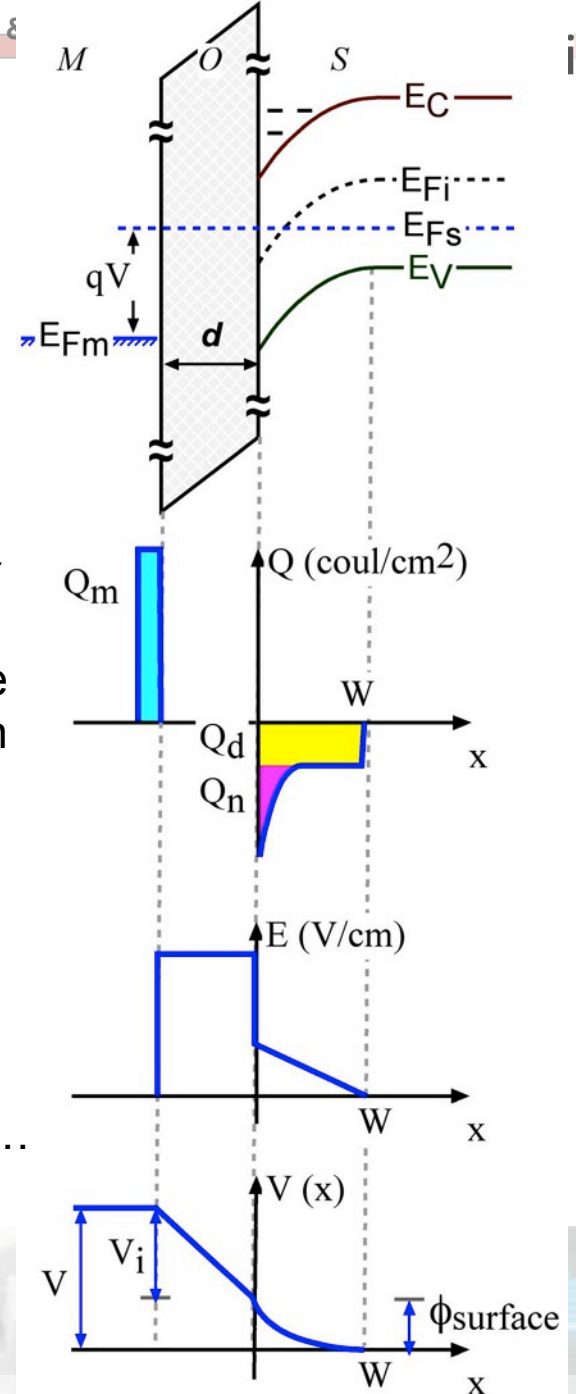
► Next, figure out how much depletion we need (we also have to pay with voltage for that too, right?).... we can treat like a n+p junction and assume all deplete into p-side:

$$W = \left[\frac{2\epsilon(V_0 - V_{app})}{q} \left(\frac{N_a + N_d}{N_a N_d} \right) \right]^{1/2}$$

$$W = \sqrt{\frac{2\epsilon_s \phi_{surface}}{q N_a}}$$

Note similarity to Debye Length...

$$L_D = \sqrt{\frac{\epsilon_s kT}{q^2 p_0}} \quad \frac{kT}{q} = \text{thermal volt.}$$



- ▶ Like a PN junction, W increases as we apply more V and further deplete the p-type material...
- ▶ However, eventually inversion sets in exponentially and takes over the charge increase as voltage is added...
- ▶ Therefore depletion region (W) stops growing at a maximum value of:

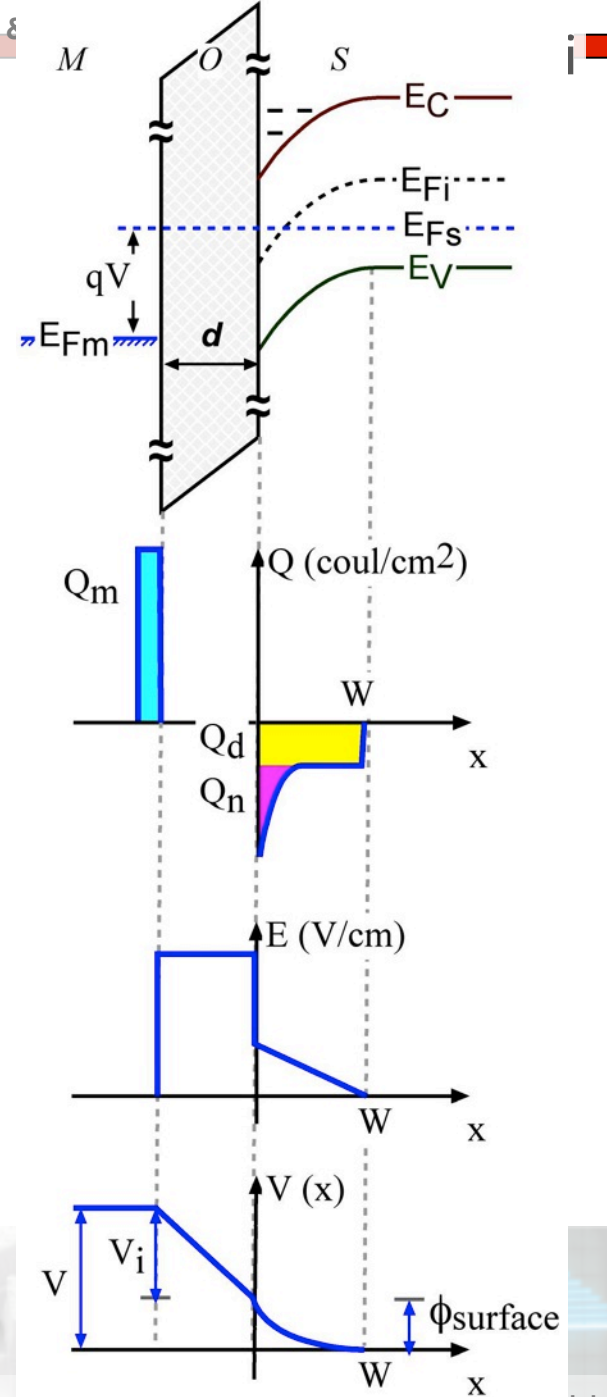
$$W = \sqrt{\frac{2\epsilon_s \phi_{surface}}{qN_a}} \quad \phi_{surface} (inv.) = 2\phi_F = 2 \frac{kT}{q} \ln \frac{N_a}{n_i}$$

↓

$$W_m = \sqrt{\frac{2\epsilon_s \phi_{surface} (inv.)}{qN_a}}$$

$$= 2 \sqrt{\frac{\epsilon_s kT \ln(N_a/n_i)}{q^2 N_a}}$$

★ **Key point! W maximizes! Inversion takes over all the new Q at some point!**



▶ We had already shown depletion charge:

$$Q_d = -qN_aW \quad (\text{coul/cm}^2)$$

▶ We can substitute W_m into Q_d

$$W_m = 2\sqrt{\frac{\epsilon_s kT \ln(N_a/n_i)}{q^2 N_a}}$$

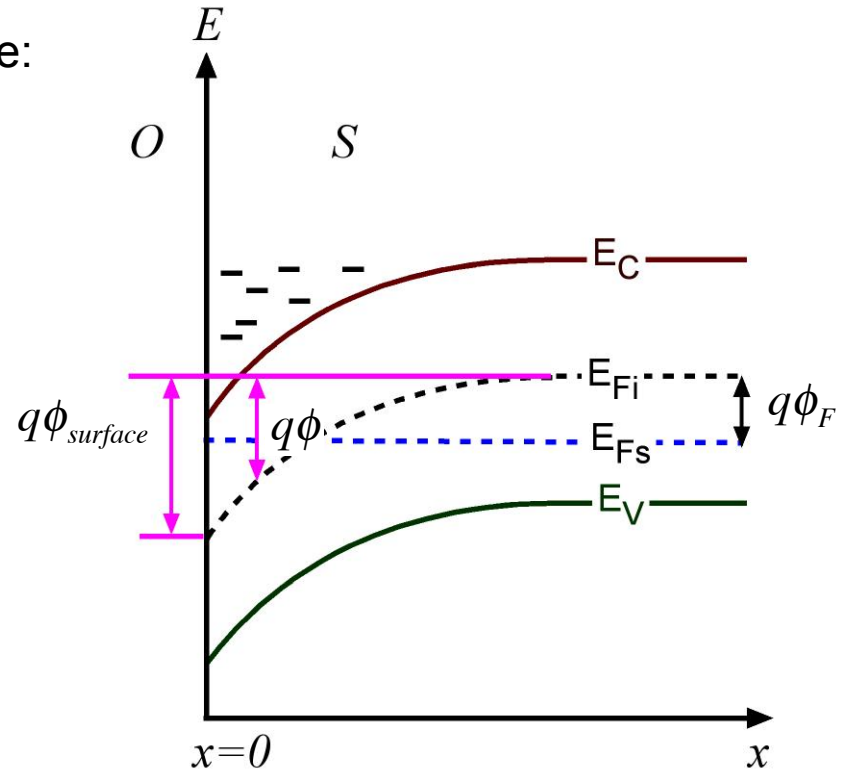
$$\frac{kT}{q} \ln \frac{N_a}{n_i} = \phi_F$$

▶ And obtain the maximum depletion charge as:

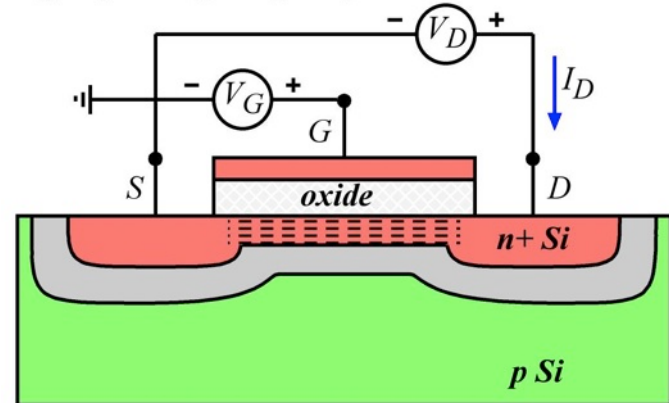
$$Q_{d,max} = -2\sqrt{\epsilon_s q N_a \phi_F} \quad (\text{coul/cm}^2)$$



HOW CAN WE TURN THIS INTO A VOLTAGE?



$$V_G > V_T \quad V_D < (V_G - V_T)$$



▶ Okay, lets calculate V_{TH} ! 1st, recall for conducting channel we need to have **strong** Inversion, *the surface should be just as n-type as the substrate is p-type...*

$$\phi_{surface} (inv.) > 2\phi_F = 2 \frac{kT}{q} \ln \frac{N_a}{n_i}$$

▶ To get the threshold voltage we therefore need $2\phi_F$

▶ However, before we could achieve $2\phi_F$ we needed to max out the depletion region, and that creates charge, and using $Q=CV$ means it requires additional voltage!

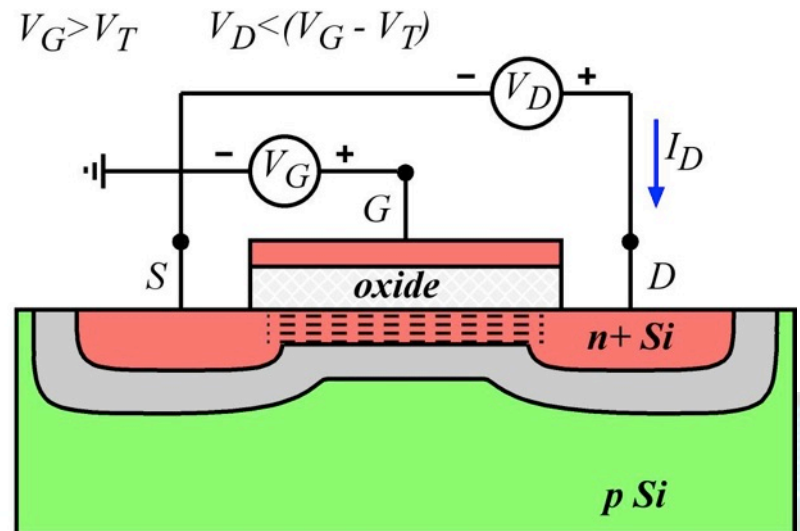
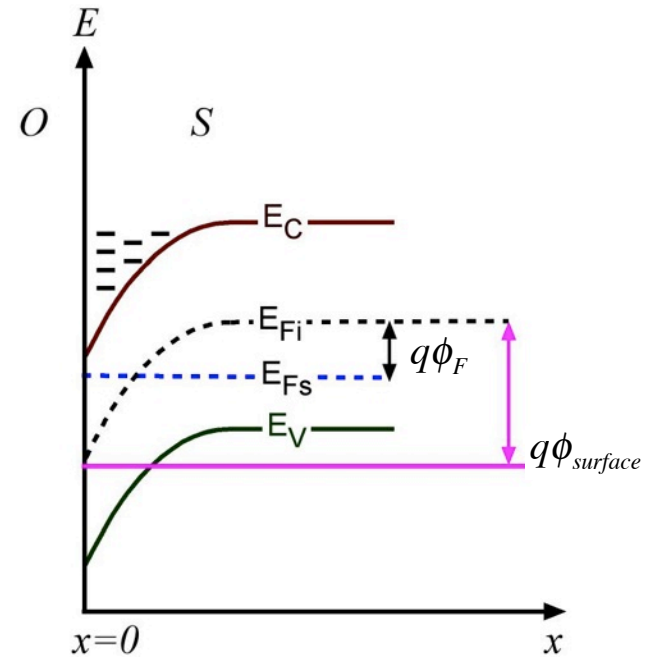
$$Q_{d,max} = -2\sqrt{\epsilon_s q N_a \phi_F} \quad (coul/cm^2)$$

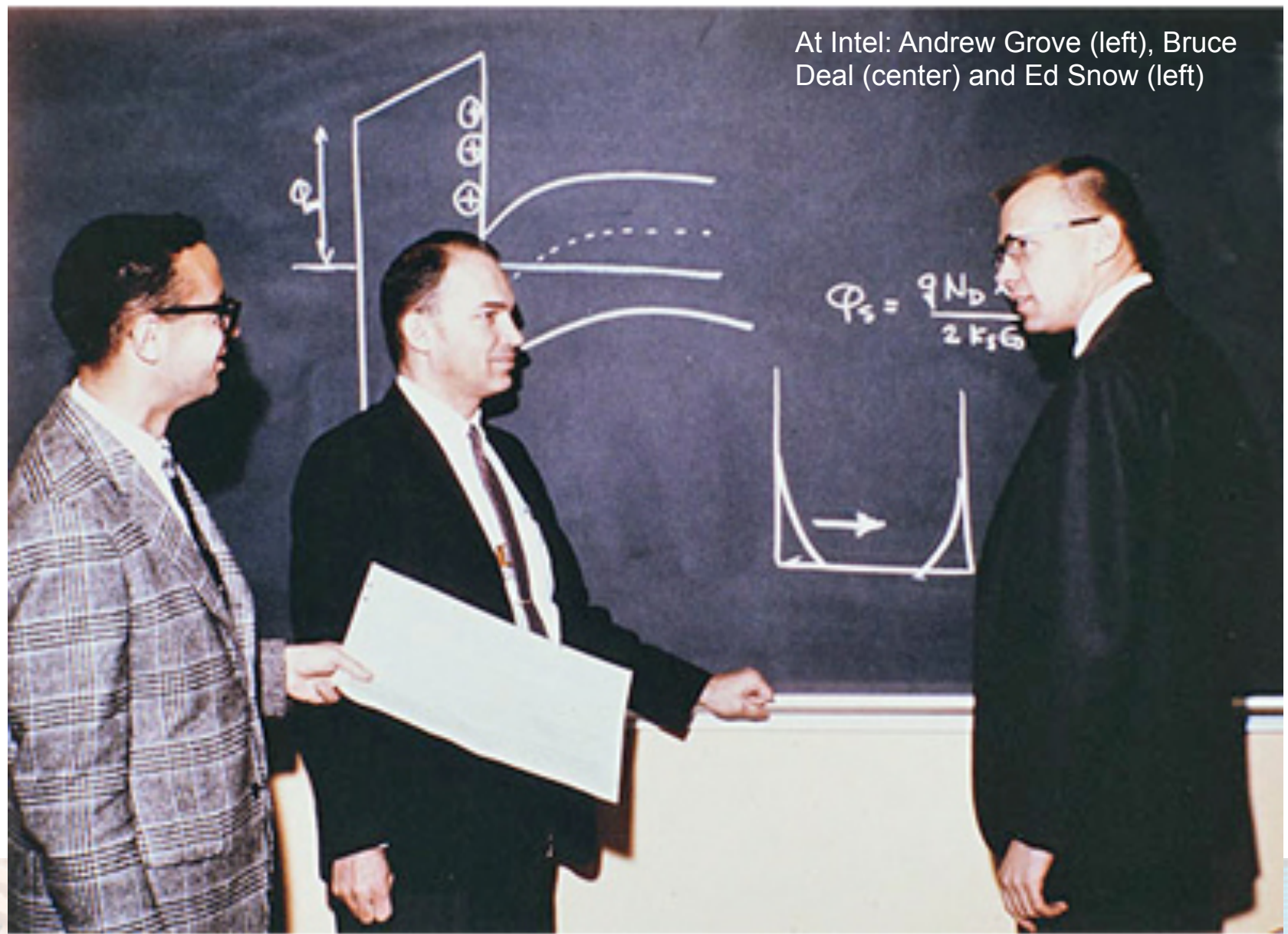
▶ Therefore the ‘ideal’ case for MOSFET threshold voltage is:



$$V_T = -\frac{Q_{d,max}}{C_i} + 2\phi_f$$

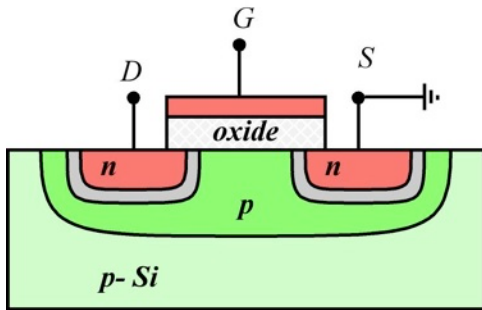
$$C_i = \epsilon/t$$





At Intel: Andrew Grove (left), Bruce Deal (center) and Ed Snow (left)

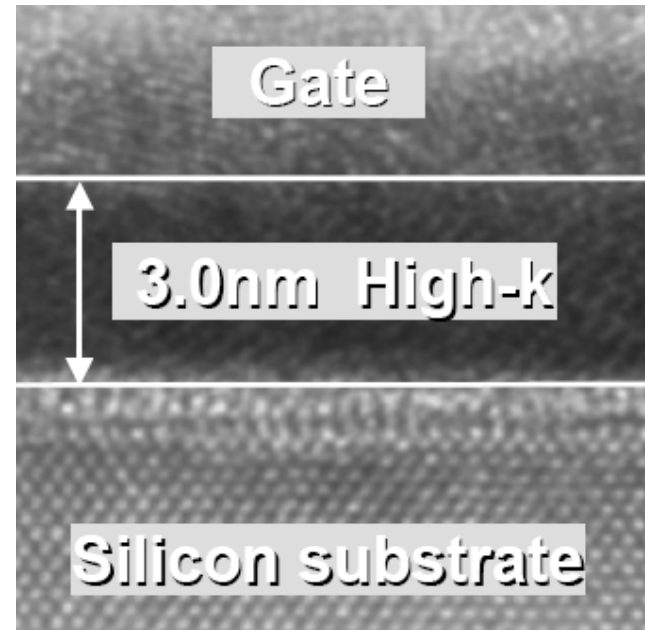
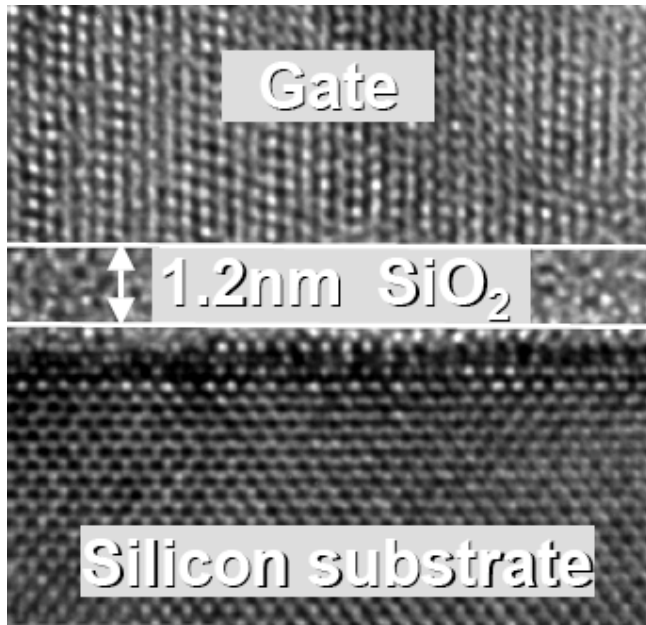




$$V_T = -\frac{Q_{d,max}}{C_i} + 2\phi_f \quad C_i = \epsilon/t$$

There is a limit to decreasing t (oxide thickness)... Why? ★

► Down to a few layers of SiO_2 molecules... chance for defects increases, and tunnel current increases... now using high k (ϵ) HfO_2 etc..



$\epsilon_r \sim 4$

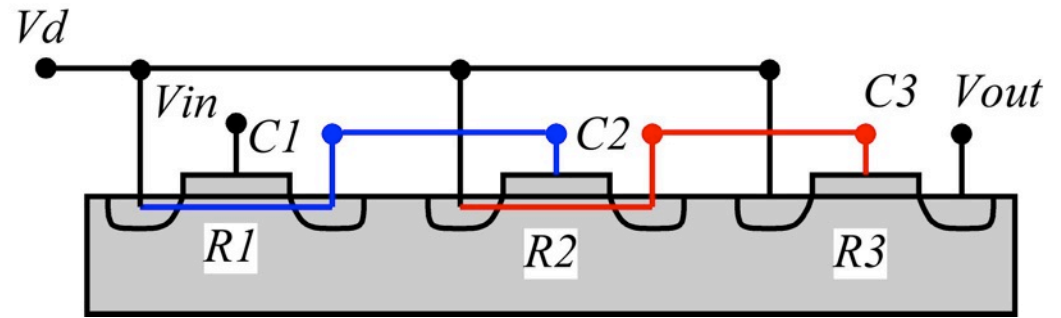
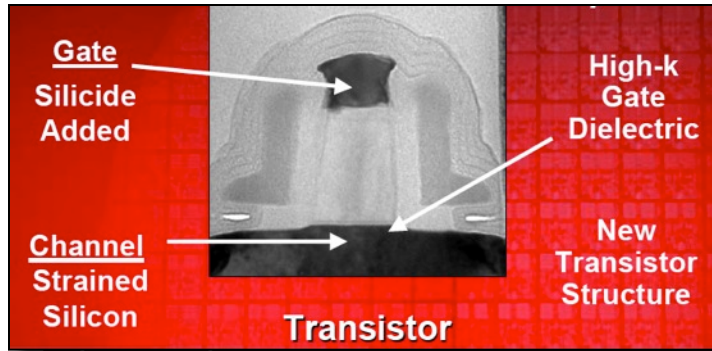
$\epsilon_r \sim 18$

What is the capacitance difference?

So why sometimes still use SiO_2 ?

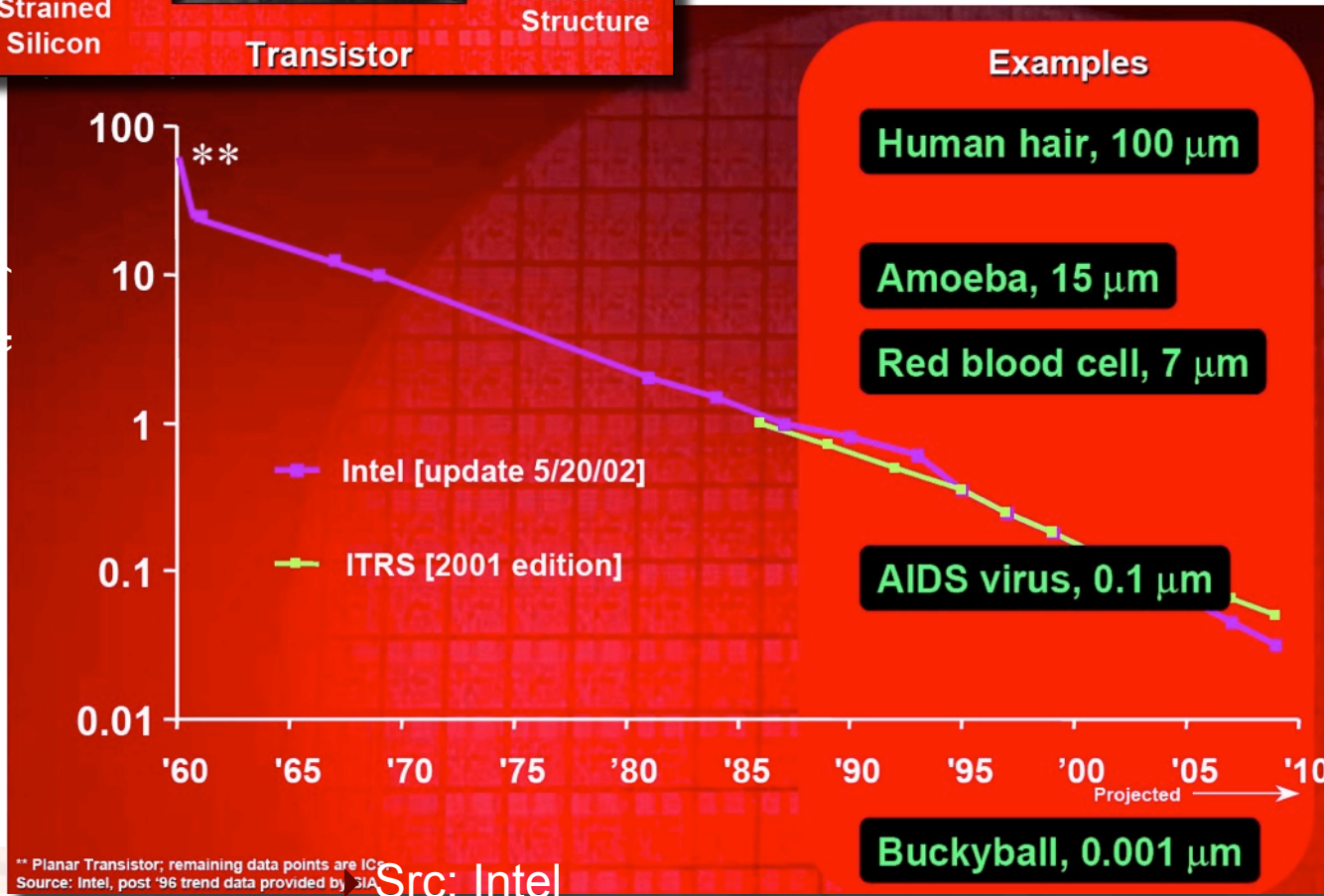


Smaller, what happens to R&C? ☆



$$\tau = R1 \times C2$$





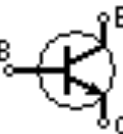

$$\tau = R2 \times C3$$



** Planar Transistor; remaining data points are ICs. Source: Intel, post '96 trend data provided by IIA

Src: Intel

- ▶ How to tell different transistors apart... (but you will find not everyone follows this!).
- So for MOSFETs, why the two parallel lines at the input? Why the 'dot' at the input of PMOS?
- For the JFETs, why no parallel lines and why the arrows at the input?

| | | |
|---|-------------------------------|--|
|  | JFET-N Transistor | N-channel field effect transistor |
|  | JFET-P Transistor | P-channel field effect transistor |
|  | NMOS Transistor | N-channel MOSFET transistor |
|  | PMOS Transistor | P-channel MOSFET transistor |
|  | NPN Bipolar Transistor | Allows current flow when high potential at base (middle) |
|  | PNP Bipolar Transistor | Allows current flow when low potential at base (middle) |

% Constants

```
eps_0 = 8.85e-14 ; % Units: F/cm
kToq = 0.0259 ; % Units: V
q = 1.6e-19 ; % Units: C
cm = 1.0e4 ; % Units: micron
```

% Parameters for Silicon

```
eps_si = 11.8 * eps_0 ; % Units: F/cm
n_i = 1.5e10 ; % Units: 1/cm^3
N_a = 1.0e16 ; % Units: 1/cm^3 <--- INPUT DOPING DENSITY
```

% Parameters for Oxide

```
eps_ox = 3.9 * eps_0 ; % Units: F/cm
d_ox = 10.0 ; % Units: nm <--- INPUT OXIDE THICKNESS
```

```
Phi_F = kToq * log( N_a/n_i ) ;
C_ox = eps_ox / (d_ox * 1e-7) ;
W_max = 2 * sqrt( (eps_si*Phi_F) / (q*N_a) ) ;
Q_d = q * N_a * W_max ;
V_T = Q_d / C_ox + 2 * Phi_F ;
```

```
V = linspace(0,1,11); % Define Range of Depletion Bias Voltages
A = (C_ox/eps_si)*(C_ox/2/q/N_a) ; a = 1/(2*A) ;
V_ox = -a + sqrt(a*a + V/A) ;
V_si = V - V_ox ;
```

```
W = sqrt( 2*eps_si*V/q/N_a) ;
```

```
X_si = linspace(0,500,51) ;
X_ox = [-10 0] ;
X_m = linspace(-50,-10,5) ;
XX = [X_m X_si];
```

```
axis( [-100 400 -1 .1]); hold on
plot( [-100 400] , [ 0 0] ) ; hold on
plot( [0 400] , [-Phi_F -Phi_F], ':' ) ; hold on
plot( [0 400] , [-2*Phi_F -2*Phi_F], ':' ) ; hold on
plot( [0 0] , [-1 .1] ) ; plot( [-10 -10] , [-1 .1] ) ;
```

```
for iV =1:11
```

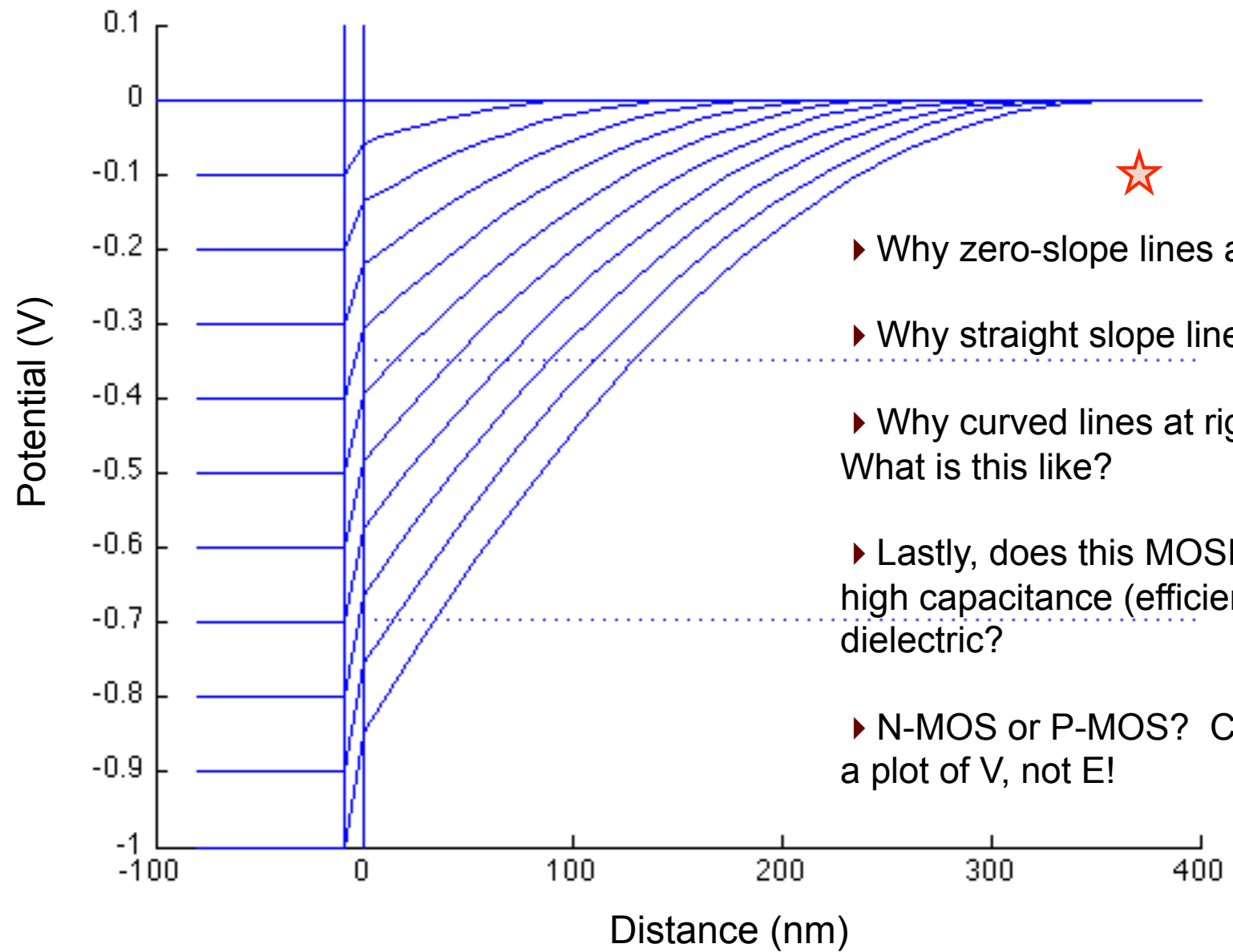
```
Vm = V(iV) ;
Vi = V_ox(iV) ;
Vs = V_si(iV) ;
WW = W(iV)*cm*1000 + 0.1 ;
```

```
xV = linspace(0,WW,15) ;
vV = Vs * (xV/WW - 1) .* (xV/WW - 1) ;
```

```
plot( [-80 -10] , [-Vm -Vm] ) ; hold on
plot( X_ox , [ -Vs-Vi , -Vs] ) ; hold on
plot( xV , -vV ) ; hold on
```

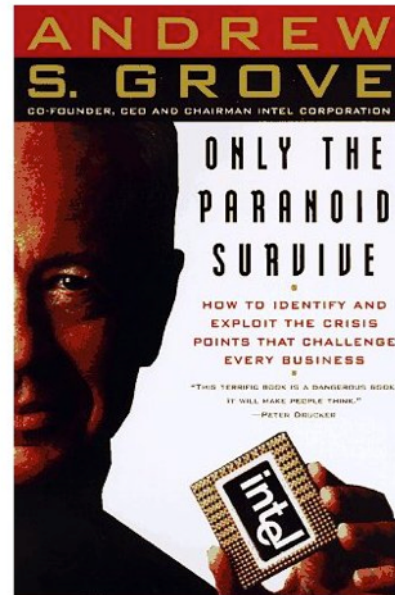
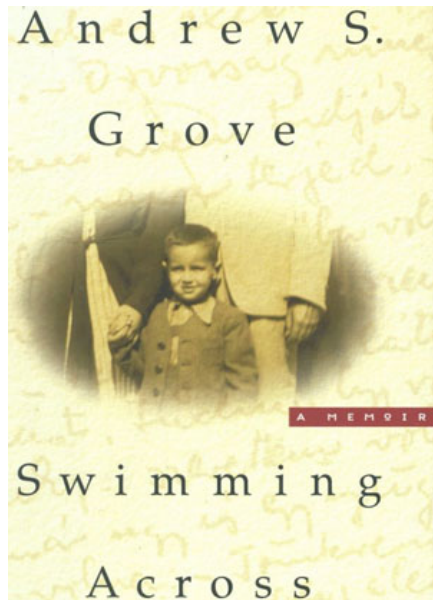
```
end
```





- ▶ Why zero-slope lines at left side?
- ▶ Why straight slope lines in middle?
- ▶ Why curved lines at right side?
What is this like?
- ▶ Lastly, does this MOSFET have a high capacitance (efficient) gate dielectric?
- ▶ N-MOS or P-MOS? Careful, this is a plot of V, not E!

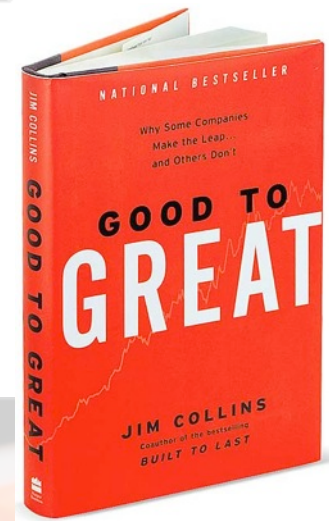
▶ Last Topic... Who is Andy Grove?



▶ First read 'Only the Paranoid Survive' to appreciate what he accomplished as an Engineer.

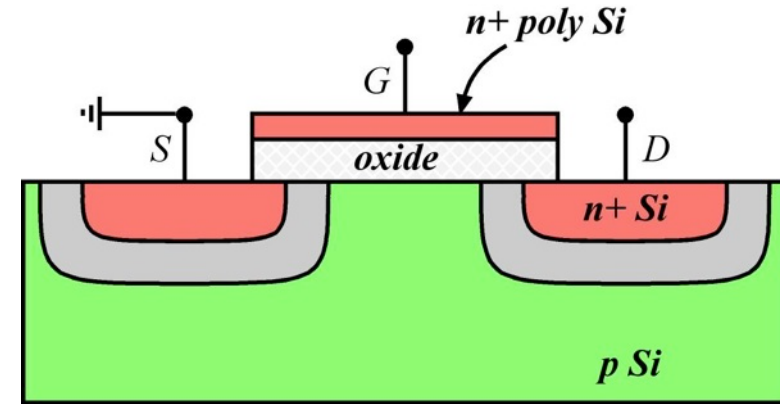
▶ Second, read 'Swimming Across' to realize how fortunate you are to be here as an EE.

▶ Third, a business-related book every engineer should read is 'Good to Great'.



► The depletion I can create under the gate oxide maximizes, why? *Hint, something else takes over that dominates mathematically in terms of charge generation...*

► Once my surface potential is (ϕ_{surf}) is above threshold voltage, at what mathematical rate are carriers created in the channel? *Hint: think back to that Q_s plot..., think how we calculate carrier concentration.*



Note – we will see next lecture, however, that surface potential and external gate voltage are not proportional...

► Why don't we see strong exponential increase in carriers until the band-bending (ϕ_s) reaches $2\phi_F$? *Hint: see the Q_s plot*

► How does the MOSFET gate voltage change if I reverse all the doping types? *No hint needed!*

► Why can't I make the oxide thinner and thinner? *One word answer will do!*

► Why do smaller MOSFETs make faster chips? *But remember, more transistors per unit area means more heat generation... which is often the limiter today...*

